



# Role of defects in organic–inorganic metal halide perovskite: detection and remediation for solar cell applications

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## Abstract

Recently, organic–inorganic metal halide perovskite materials have shown great potential for the next generation low-cost renewable energy generation source, and it has surpassed the power conversion efficiency (laboratory scale) of most of the commercially available solar absorbers. Despite the ubiquity and robustness of perovskite materials for defect tolerance in solar cells, its high intrinsic/extrinsic defects remain a bottleneck for real-time application. Thus, a thorough understanding of defect formation and their impact on various recombination losses is a requisite solution for this technology. In this review, we have focused on the formation of various defects and their role in material optoelectronic properties. Further, detailed case studies of each defect via various experimental techniques, their detection and remediation are discussed. Furthermore, the defect detection and remediation approach represent a key step (where optoelectronic properties of the absorber layer can be easily tuned) forward in the sustainable synthesis, fabrication and evaluation of perovskite solar cells.

## 1 Introduction

Metal halide perovskites ( $ABX_3$ , where  $A = MA^+$  ( $CH_3NH_3^+$ ),  $FA^+$  ( $HCNH_2^+$ ),  $Cs^+$ ,  $B = Pb^{2+}$ ,  $Sn^{2+}$ ,  $X = I^-$ ,  $Br^-$ ) have gained a tremendous popularity in a short span for solar cell application after its first use in 2009 by Miyasaka et al. [1] The power conversion efficiency (PCE) has increased from a feeble 3.8 to 25.5% [2] which is close to the state-of-the-art silicon-based solar cells. [3] Unique physical properties such as remarkably high diffusion length [4], high charge carrier mobilities, solution [5] and low temperature processability [6] make perovskite a highly attractive low-cost [7] alternative material compared to the conventional solar cell absorbers such as GaAs, CdTe and crystalline silicon. In order to achieve PCE, close to its Shockley–Queisser limit [8], the underlying physical manifestation of charge carrier defects formed due to the presence of imperfection in perovskite crystals is of utmost need to explore and understand. This review covered the wide variety of physical phenomenon ranging from the defect kinetic, defect dynamics and recombination mechanism. The classification

of different type of defects and their kinetics based on the thermodynamic principles is discussed. Secondly, the activation energy of the defect formation in perovskite is discussed based on first principle calculations. Further, various recombination mechanisms due to the presence of defects (non-radiative recombination, radiative recombination and Auger recombination) are discussed in details. Last but not least, we have described the various experimental strategies which are being currently employed for the defect mitigation in perovskite such as the use of material engineering, grain boundary passivation, interfacial engineering and antisolvent vapor-assisted processes.

### 1.1 Thermodynamic efficiency

Assuming solar cell as a heat converter working between 6000 K (temperature of the sun) and 300 K (ambient temperature). The Carnot efficiency formula (Eq. 1.1) can be applied to calculate the upper power conversion efficiency limit for such a solar converter. [9]

$$\eta = 1 - \frac{T_A}{T_S} \quad (1.1)$$

It is possible to obtain an upper PCE of 95%, but thermal efficiency limit does not consider the entropy-related losses that are dominant inside the solar converter. According to the Kirchhoff law of radiation, any blackbody maintained at

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thermal equilibrium with surrounding will reemit the radiation with the same rate as it is absorbing. To incorporate these entropy-related losses, one has to incorporate radiation reemission factor from a solar converter maintained at a finite temperature  $T_C$ .

In order to consider entropy-related losses for the PCE, blackbody efficiency calculation formula as described in Eq. 1.2 has to be invoked. [9]

$$\eta = 1 - \left( \frac{T_C^4}{T_S^4} - \frac{4T_A}{3T_S} - \frac{4T_A}{3T_C} \times \frac{T_C^4}{T_S^4} \right). \quad (1.2)$$

It is possible to obtain a maximum PCE of 86% when the temperature of a converter is maintained at 2500 K. However, terrestrial-based solar cell absorbers cannot withstand such a high temperature; therefore we need to explore the more practical limit for the absorber material maintained at ambient temperature. One such limit was proposed by Shockley and Queisser in 1961 and famously known Shockley-Queisser limit (SQL) of the PCE. [8] In the next section, we have described about this limit and its consequence on solar cell parameters. This PCE limit is also known as radiative PCE limit of solar cell because authors have only considered radiative recombination as the only mechanism responsible for the charge carrier recombination. Detailed study on the impact of radiative recombination process on perovskite semiconductor physical properties is described in the Sect. 4 of this article.

## 1.2 Shockley-Queisser efficiency limit

In practical solar cells, we have to consider the impact of the finite bandgap ( $E_g$ ) of the absorber layer. Shockley and Queisser considered a semiconductor material having a bandgap of  $E_g$  with a sharp cutoff frequency ( $\nu_g$ ). Since solar cells are essentially a solid state  $p$ - $n$  junction diode, authors assumed a unity light absorption coefficient for all the photon frequencies greater than the cutoff frequency of semiconductor. Further, it has been assumed that the radiative recombination is present in the material with single  $e$ - $h$  pair generation per single incident photon absorption. Before considering the impact of finite temperature on PCE of solar cell, Shockley and Queisser calculated ultimate PCE for a solar converter maintained ideally at  $T=0$  K. The input power incident on solar cell is given by Eq. 1.3. [9]

Incident power =  $Ap_s$ , where  $p_s$  is given by

$$p_s = \frac{2\pi h}{c^2} \int_0^\infty \frac{\nu^3 d\nu}{\left( \exp\left(\frac{h\nu}{KT}\right) - 1 \right)} \quad (1.3)$$

$p_s$  is the total amount of radiation incident on solar converter in accordance with Plank's law of radiation, and  $A$  is

the total device area under consideration. The magnitude of the total output power is given by the relation, output power =  $h\nu A q_s$ , where  $q_s$  is the amount of radiation absorbed by the semiconductor above the cutoff frequency  $\nu_g$  given by Eq. 1.4 [8].

$$q_s = \frac{2\pi}{c^2} \int_{\nu_g}^\infty \frac{\nu^2 d\nu}{\left( \exp\left(\frac{h\nu}{KT}\right) - 1 \right)}. \quad (1.4)$$

Since PCE is the ratio of output power generated by the device divided by the input power incident on the device, so the PCE  $\eta$  is given by Eq. 1.5 [8].

$$\eta = \frac{h\nu_g q_s A}{Ap_s} \quad (1.5)$$

According to Eq. 1.5, it is possible to obtain a PCE of 44% assuming sun to be maintained at temperature of 6000 K and solar cell to be maintained at 0 K temperature. But this PCE is again not possible because one has to incorporate the finiteness of temperature and also the finiteness of geometrical cross-sectional area of the solar cell. As discussed in the blackbody radiation efficiency limit because of the finite temperature of the solar cell, it is bound to emit radiation in accordance with the Kirchhoff law. In order to calculate steady-state response of the solar cell maintained at finite temperature (300 K), one needs to consider all the dynamical process happening inside the solar cell. Shockley and Queisser identified five such different dynamic processes, and we have defined these different processes as discussed below.

1. Rate of generation of  $e$ - $h$  pair due to the absorption of incident photon, and it is denoted by the symbol  $G_s$ .
2. Radiative recombination of  $e$ - $h$  which will lead to the emission of photons. It is denoted by the symbol  $G_c(V)$ , where  $V$  is the magnitude of quasi-Fermi level splitting due to the incident radiation.
3. Other non-radiative process which leads to generation, and it is denoted by the symbol  $R(0)$ .
4. Non-radiative recombination of  $e$ - $h$  pair due to quasi-Fermi level splitting and it is denoted by the symbol  $R(V)$ .
5. Removal of photogenerated  $e$ - $h$  pair from the active layer which will generate a current density  $J$  at the rate of  $J/q$ .

For the steady-state response of solar cell: [8]

$$G_s - G_c(V) - R(0) - R(V) - \frac{J}{q} = 0 \quad (1.6)$$

where positive sign is used for the generation of charge carriers in the device, and negative sign is used for removal or recombination of charge carriers out of the device.  $R(V)$  and  $G(V)$  are related to  $R(0)$ ,  $G(0)$  by the relation  $R(V) = R(0)\exp(V/V_C)$  and  $G(V) = G(0)\exp(V/V_C)$  respectively.  $V_C$  is the thermal voltage equivalent of device operating temperature. On solving Eq. 1.6, steady-state  $JV$  response of the solar cell can be obtained, and it is given by Eq. 1.7 [8].

$$J = J_0 \left[ \exp\left(\frac{V}{V_C}\right) - 1 \right], J_0 = q(G_C(0) + R(0)) \quad (1.7)$$

Under light illumination condition,  $JV$  response of solar cell is given by Eq. 1.8 [8].

$$J_{rad}|_V = J_0 \left[ \exp\left(\frac{V}{V_C}\right) - 1 \right] - J_{SC} \quad (1.8)$$

where  $J_{SC}$  is the short circuit current density and  $J_{rad}$  is the radiative limit of the maximum current at the short circuit condition of the solar cell. In order to obtain open circuit voltage ( $V_{OC}$ ) of the solar cell,  $J=0$  was set inside Eq. 1.8, and the radiative limit for the open circuit voltage is given by Eq. 1.9. [9]

$$J = 0, V_{OCrad} = \frac{KT}{q} \ln \left[ \left( \frac{J_{SC}}{J_0} \right) + 1 \right] \quad (1.9)$$

In order to get maximum PCE, one has to maximize the product of  $JV$ , and the PCE (Eq. 1.10) of a solar cell is given

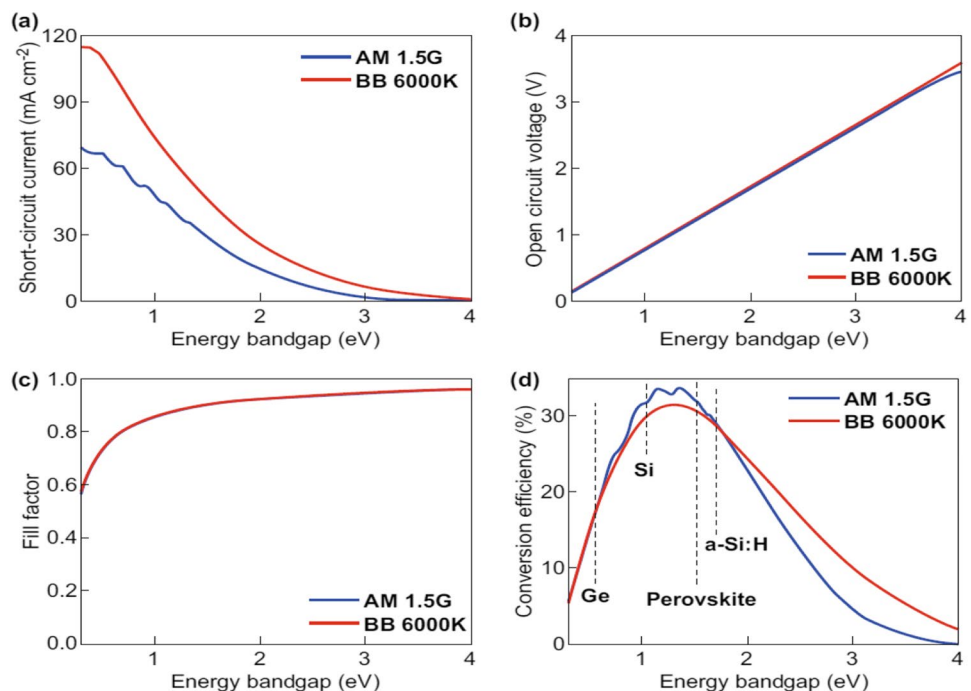
by product of  $J_{MAX}$  and  $V_{MAX}$  at the maximum voltage condition divided by the amount of incident input power. [8]

$$\frac{dP}{dV} = \frac{d(JV)}{dV} = 0$$

$$\eta = \frac{J_{MAX} V_{MAX}}{P_{inc}} \quad (1.10)$$

Maximum possible radiative PCE for a single junction solar cell is found to be approximately around 33% with a bandgap of semiconductor in the range 1.2–1.4 eV [8, 9], and the radiative limit for  $V_{OC}$  and  $J_{SC}$  is defined by Eqs. 1.8 and 1.9 respectively. In order to surpass this efficiency limit, one has to employ the other techniques such as designing a tandem solar cell [10] and hot carrier solar cell [11], but these techniques are beyond the scope of this article. The maximum PCE is a product of the short circuit current and the open circuit voltage. It is possible to increase the  $V_{OC}$  of the device simply by increasing the bandgap of the active layer, but at the same time this will hamper the short circuit current of the device since lesser number of photons are now being absorbed inside the active layer. Figure 1a, b, c, d illustrates the variation in PCE,  $V_{OC}$ ,  $J_{SC}$  and FF of a solar cell as a function of semiconductor bandgap. The  $V_{OC}$  of a solar cell is observed to be increasing linearly with the increase in the energy bandgap of semiconductor, and  $J_{SC}$  is observed to be decreasing with the increase in the energy bandgap of the semiconductor. Since PCE of solar cell is proportional to the product of  $V_{OC}$  and  $J_{SC}$  of solar cell,

**Fig. 1** (a) Variation of  $J_{SC}$  with the change in the bandgap of semiconductor, (b) variation of  $V_{OC}$  with the change in the bandgap of semiconductor, (c) variation of FF with the change in the bandgap of semiconductor, (d) variation of PCE due to incident of blackbody spectrum at 6000 K and AM 1.5G spectrum with the change in the bandgap of semiconductor [9]



hence firstly it is observed to increase with the increase in the bandgap and then decreases before peaking in the energy bandgap regime 1.2–1.4 eV. These values of various solar cell parameters are only based on the radiative recombination; therefore, one has to consider the other recombination mechanisms as well to explain the observed results of solar cell various parameters.

### 1.3 Recombination processes in semiconductors

Different recombination processes hinder the upper PCE limit, as SQL takes into consideration only radiative recombination process. Due to the presence of various other recombination mechanisms in the semiconductor, achieving SQL is difficult. In this section, we have described fundamental of different recombination pathways, experimental techniques and few of the case studies in order to develop a deeper understanding about recombination in perovskite-based semiconductors. Semiconductor recombination processes are divided into three categories namely radiative recombination (bimolecular), non-radiative recombination (monomolecular) and Auger recombination. These are the relaxation processes of free charge carriers in the semiconductor material after it is being subjected to external perturbation such as light irradiation or voltage. After the radiative recombination relaxation process, semiconductor will emit a radiation (photon) out of the system, and the magnitude of the recombination process depends upon the product of electron and hole concentration. While the other two recombination processes are non-radiative in nature and relax through emission of phonons inside the material. The rate of monomolecular recombination is directly proportional to the density of trap states ( $N_T$ ) present in the material, while Auger recombination is a three-particle phenomenon as discussed in more detail in the latter section. All three different processes have different rate constant and hence different time scale of charge carrier's relaxation. Charge carrier lifetime in a semiconductor due to the presence of different recombination processes is given by Eq. 1.11 [12].

$$\frac{1}{\tau_{eff}} = \frac{1}{\tau_{NR}} + \frac{1}{\tau_R} + \frac{1}{\tau_A} \quad (1.11)$$

where  $\tau_{eff}$  is the effective bulk lifetime of charge carriers and  $\tau_{NR}, \tau_A, \tau_R$  are the charge carrier lifetime dictated by the non-radiative, Auger and radiative recombination processes respectively. The rate equation of photogenerated charge carrier decay can be written as Eq. 1.12 [13].

$$\frac{dn}{dt} = -(k_1 n + k_2 n^2 + k_3 n^3) = -nR \quad (1.12)$$

where  $K_1, K_2, K_3$  are the rate constants for the non-radiative, radiative and Auger charge carrier recombination

processes respectively and  $R$  is known as the total recombination rate of the device. The effective lifetime of charge carrier can also be written as described below in Eq. 1.13 [14].

$$\tau_{eff} = \frac{\Delta n}{R} \quad (1.13)$$

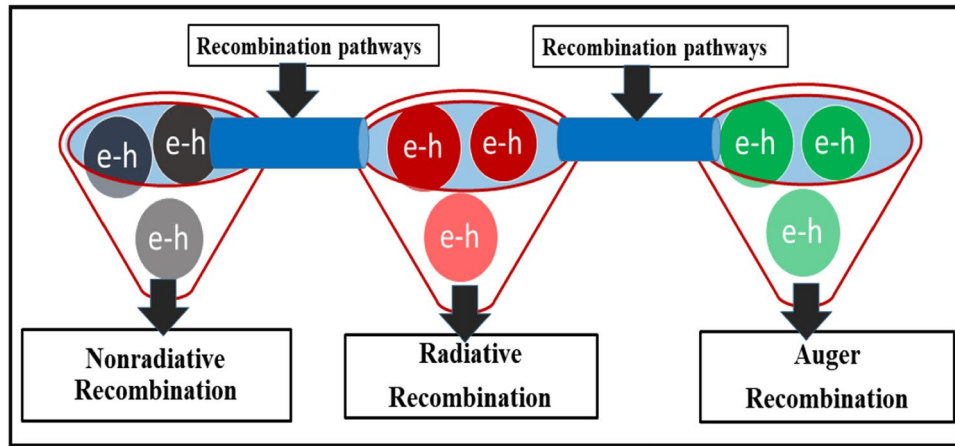
$\Delta n$  is the photo-induced charge carrier excitation density. By combining Eqs. 1.12 and 1.13, the charge carrier lifetime for individual recombination process can be written as  $\tau_{NR} = 1/K_1$ ,  $\tau_R = 1/nK_2$ ,  $\tau_A = 1/n^2K_3$ . With any semiconducting material having simultaneous presence of all three different recombination processes at certain experimental condition, the process with the lowest amount of lifetime will dominate the overall recombination.

Typically, microcrystalline thin films such as perovskite have defect density in the range of  $10^{14}/\text{cm}^3$  to  $10^{17}/\text{cm}^3$  [15]. Hence, if the incident photon density lies in this range, usually the monomolecular recombination process starts to dominate. At the incident photon density comparable or higher than the  $10^{17}/\text{cm}^3$ , the monomolecular recombination channel will saturate and the bimolecular recombination starts to dominate in the semiconductor (Fig. 2). For higher incident photon densities, bimolecular recombination channel alongside monomolecular also saturates and Auger recombination becomes the dominate recombination process.

### 1.4 Monomolecular recombination

$K_1$  is known as the rate constant for non-radiative recombination process of the semiconductor material. The source of non-radiative recombination is the deep lying defect energy states present inside the bandgap of a semiconductor. These defect energy level can arise due to the presence of various defects such as point defects, surface states (dangling bonds), grain boundaries and other dislocations. The mathematical model to define non-radiative recombination in the semiconductor is given by Shockley, Read and Hall (SRH recombination model). [14] This is the statistics model of non-radiative recombination mechanism happening in a semiconductor material due to the presence of single defect level inside the semiconductor bandgap at the energy level location  $E_T$  with the defect density  $N_T$ . Four different recombination processes such as  $R_1$  being the rate of electron capture by the traps,  $R_2$  is the rate of electron emission by the traps and  $R_3$  and  $R_4$  being the hole emission and capture rates due to the traps dominate respectively. At thermal equilibrium condition, the net recombination rate of electron capture and emission must be equal to the net rate of capture and emission of holes as given by Eq. 1.14 [14].

$$R = R_1 - R_2 = R_3 - R_4 \quad (1.14)$$



**Fig. 2** ‘The Bucket analogy’: This is the illustration of the dominance of one type of recombination process over the other type of recombination process in typical microcrystalline perovskite-based thin films. We have denoted three recombination processes by the three different buckets of water (water ~ photogenerated charge carriers) since three buckets are connected in series by a connector (~ recombination path-

ways) at the top of each bucket. In case of perovskite thin films, only if the bucket 1 (~non-radiative recombination center) is completely filled (or saturated) water will pass through into bucket 2 (~radiative recombination), and only if bucket 2 is filled water will pass through in the bucket three (~ Auger recombination)

The rate of overall recombination due to the presence of a single defect inside the semiconductor bandgap is given by Eq. 1.15 [16, 17].

$$R = \frac{N_T V_{th} \sigma (np - n_i^2)}{(n + p + 2n_i \cosh(\frac{E_t - E_i}{KT}))} \quad (1.15)$$

where  $V_{th}$  is the thermal velocity,  $\sigma$  is the cross-section area,  $n_i$  and  $E_i$  are the intrinsic carrier concentration and intrinsic energy location of the bandgap respectively. The rate of recombination is observed to be maximum whenever  $E_t = E_i$ , i.e. if the trap level is located in the middle of the semiconductor bandgap and such trap levels are also known as deep level traps. As the trap levels moves away from the middle of the bandgap and towards the conduction band or valance band edges, the non-radiative recombination rate starts to decrease; such defect levels are also known as shallow defect levels. The SRH lifetime of charge carrier is given by the relation  $\tau_{SRH} = (v_{th} \sigma N_T)^{-1}$ .

### 1.5 Radiative recombination

As discussed earlier in the rate Eq. 1.12,  $K_2$  is known as the bimolecular radiative recombination coefficient. Whenever charge carriers from the top of conduction band recombine with the bottom of the valance band, radiation is emitted in the form of photons. Using the optical reciprocity relation radiative recombination coefficient,  $K_2$  can be calculated as shown below in Eq. 1.16. [18]

$$K_2 = \frac{\int_0^\infty 4\alpha(E) n_r^2 \phi_{bb} dE}{n_i^2} \quad (1.16)$$

$\alpha(E)$ ,  $n_i$  are the light absorption coefficient and refractive index of the semiconductor material, and  $\phi_{BB}$  is the incident solar flux given by the Plank’s law of radiation, and it is given by Eq. 1.17 [18].

$$\phi_{bb}(E) = \frac{2\pi E^2}{h^3 C^2} \left[ \frac{1}{\exp\left(\frac{E}{KT} - 1\right)} \right] \quad (1.17)$$

By the principal of optical reciprocity, any good absorbing semiconductor material is also a very good radiation emitter. Because radiative recombination pathways are the same as light absorption pathways, but this is not true in case of the non-radiative recombination pathways [19]. A good quality solar cell should emit radiation as much as it absorbs under the open circuit voltage condition. [19–21] As described earlier, radiative recombination is a two particle phenomenon; hence, the total recombination rate will depend upon the product of the electrons and holes, and its expression is given by Eq. 1.18 [18].

$$R = K_2 np = K^2 n_i^2 \exp\left(\frac{\Delta E_F}{KT}\right) \quad (1.18)$$

### 1.6 Auger recombination

Auger recombination is a third-order recombination process widely observed in different semiconductors. It is three particle phenomena where after the initial radiative recombination



of photogenerated charge carrier, the emitted photon is again re-absorbed by an electron or hole. After absorbing the photon, electrons in the conduction (holes in valance band) band become a hot electron and relax back to thermal equilibrium by emitting the multiple phonons. Such a process is also known as the impact ionization of charge carriers. Auger recombination is also a non-radiative process in nature. Auger recombination can be divided into multiple types, and the various recombination rates are listed below in Eq. 1.19. [22] Auger recombination can also process through reabsorption of emitted photon due to the trap level present inside the bandgap. Typical Auger recombination rate is given as

$$\left. \begin{aligned} R_{aug} &= K_3 n^2 p \\ R_{aug} &= K_3 n p^2 \\ R_{aug} &= K_3 n p N_T \end{aligned} \right\}. \quad (1.19)$$

$K_3$  is the Auger recombination rate constant. By neglecting the Auger recombination due to trap states and using Eq. 1.19, total Auger recombination can be written as [22]

$$R_{aug} = K_3 n^2 p + K_3 p^2 n. \quad (1.20)$$

By assuming  $n = p$  which holds very much true for an intrinsic semiconductor such as a perovskite, Eq. 1.20 can be rewritten as [22]

$$R_{aug} \propto K_3 n^3. \quad (1.21)$$

Using the relation  $np = n_i^2 \exp\left(\frac{qV}{KT}\right)$  [17] and substituting in Eq. 1.21 [22], the Auger recombination rate can be written as

$$R_{aug} \propto K_3 n_i^3 \exp\left(\frac{qV}{3KT}\right). \quad (1.22)$$

Auger recombination typically dominates in the carrier density regime of 100 s order magnitude higher than the usual operating condition of the solar cell, so for the terrestrial thin film-based solar cell Auger recombination is a negligible phenomenon. Auger recombination plays a vital role under large illumination injection and at high doping density levels. [22] Detailed study of Auger recombination using SRH like statistics model can be found in a study recently published by Staub et al. [23].

## 2 Defects type, kinetics and their formation energy in perovskite semiconductors

### 2.1 Defects in perovskite

Defect formation in materials is inevitable in nature because solidification always takes place at finite temperature ( $> 0$  K). The presence of imperfections strongly influences

the properties of materials; thus, to understand their role in the physical parameter alternation is highly important. [24–26] Crystalline defects are simply defined as the lattice irregularity at the atomic scale in one or more than one dimensions, and such defects are classified mainly into four different categories namely zero-dimensional point defects and extended dimensional defects such as one dimensional (screw and edge dislocation), two dimensional (stacking faults, grain boundaries) and three-dimensional defects such as aggregation of the impurities. Defects modify the electronic structure of semiconductor by introducing the energy level inside the bandgap of semiconductor. The optoelectronic properties of semiconductor material are highly influenced by the type of defect present in the semiconductor material and the energy states created by the defects [27]. The carrier diffusion length and charge carrier lifetime of solar cell absorber are important parameters for determining the quality of solar cells, and these two parameters are highly influenced by the type of defects present inside the material. [28] Shallow level point defects are observed to have low formation energy in MAPbI<sub>3</sub>-based perovskite, while deep level defects are observed to have high formation energy. [29, 30] Halide perovskite-based semiconductors possess a massive number of intrinsic point defects, and it is very important to understand the thermodynamic stability, intrinsic point defect formation mechanism and the kinetics of defect formation in halide perovskites.

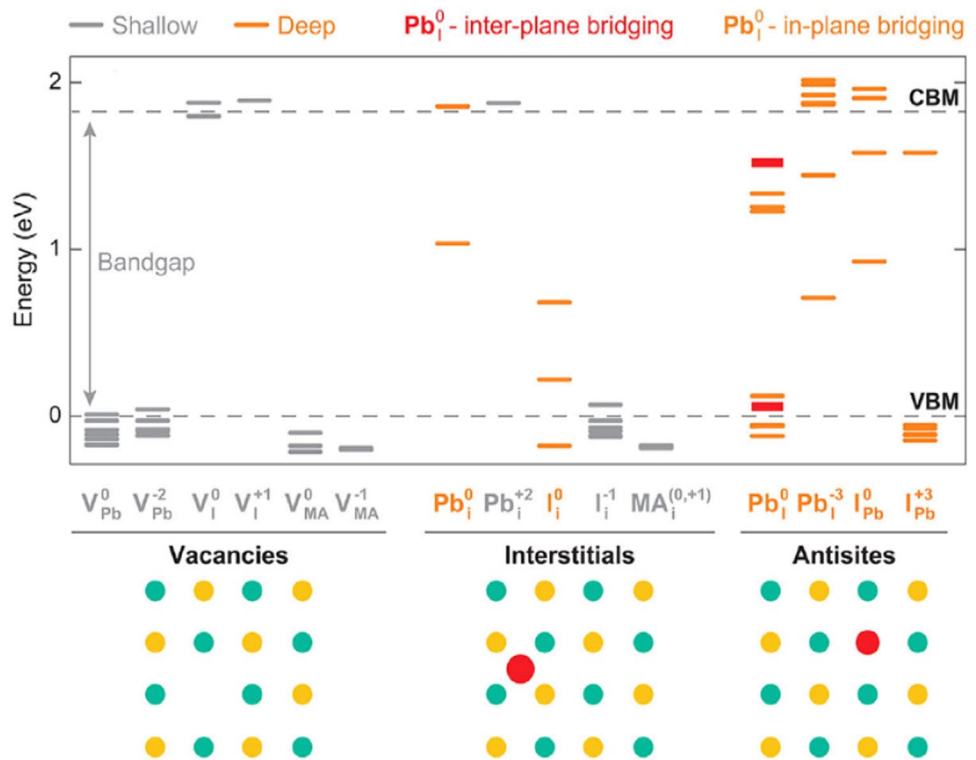
### 2.2 Kinetics of defect formation

Yin et al. studied the defects in MAPbI<sub>3</sub> and predicted that the defect formation energies dominantly create shallow level states inside the bandgap of MAPbI<sub>3</sub>. [30] The defect study suggests that Pb<sup>2+</sup>, MA<sup>+</sup>, I<sup>−</sup> create shallow donor and acceptor level states as described below in Fig. 3. In general, perovskite material is observed to show the formation 12 types of point defects. Three vacant point defects correspond to the missing MA<sup>+</sup>, Pb<sup>2+</sup>, I<sup>−</sup> ions from their respective lattice sites and are denoted by the symbol V<sub>MA</sub>, V<sub>Pb</sub>, V<sub>I</sub> respectively. The migration of MA<sup>+</sup>, Pb<sup>2+</sup>, I<sup>−</sup> to the interstitial site denoted by the symbol MA<sub>i</sub>, Pb<sub>i</sub>, I<sub>i</sub> respectively is observed to cause interstitial point defects. The substitution of cations by the anions such as MA<sub>I</sub>, I<sub>MA</sub>, Pb<sub>I</sub> and I<sub>Pb</sub> is known as the antisite point defects, while MA<sub>Pb</sub> and Pb<sub>MA</sub> are known as the substitutional point defects.

Defect formation energy in MAPbI<sub>3</sub> was derived by Walsh et al. [32] using the Kröger and Vink notations as described below in Eqs. 2.1–2.3. Authors have considered the reaction of partial and full Schottky disorder with respect to MAI and PbI<sub>2</sub> sub lattices.

Partial Schottky disorder reaction is given by Eqs. 2.1 and 2.2 [32].

**Fig. 3** Schematics of energy levels associated with the various defect states vacancies ( $V_{Pb}$ ,  $V_I$ ,  $V_{MA}$ ), neutral and charged interstitials ( $Pb_i$ ,  $I_i$ ,  $MA_i$ ), states associated with antisites ( $Pb_i$  and  $I_{Pb}$ ) present inside the bandgap of MAPbI<sub>3</sub> calculated using the first principle analysis [31]



Full Schottky disorder reaction is given by Eq. 2.3 [32].



where Nil represents the ordered MAPbI<sub>3</sub> lattice,  $V''$  is the vacant site due to the missing divalent cation and  $V'$ ,  $V^{\circ}$  represent the missing vacant site due to monovalent cation, vacancy due to the missing halide anion respectively. The ionic species and effective defect charges are represented in subscript and superscript respectively. Reaction 3 preserves the overall stoichiometry ratio within the material, and reactions 1, 2 are non-stoichiometric in nature. Since due to high atomic radius of halide ions, there is not enough interstitial space available for halide ions to migrate interstitial so  $I^-$ ,  $Pb^{2+}$  and  $MA^+$  vacancy mediated diffusion is the most common defect reaction observed in the perovskite semiconductors. The three-vacancy transport mechanism reported by Eames et al. [33] is based on the hopping of ions between the neighboring positions such as the migration of  $Pb^{+2}$  within the cubic unit cell along the diagonal direction  $\langle 110 \rangle$ , migration of  $I^-$  along the octahedral edge and the migration of  $MA^+$  into the vacant A site position. The equilibrium

concentration can be calculated thermodynamically using the law of mass action given by Eq. 2.4 [32].

$$[V'_{MA}][V^{\circ}_{Pb}][V^{\circ}_I]^3 = K_C = K_C^{\circ} \exp\left(-\frac{\Delta H_S}{KT}\right) \quad (2.4)$$

where  $K_C$  is the fraction of the lattice sites and  $K_C^{\circ}$  are the vacant sites due to the reaction enthalpy ( $\Delta H_S$ ). The stoichiometric of MAPbI<sub>3</sub> phase can be controlled by the growth conditions because the dissociation energy of this perovskite to MAI and PbI<sub>2</sub> is very low value at 0.27 eV.

### 2.3 Defects and their formation energy

The second phase formation due to change of temperature in the perovskite is avoided by controlling the growth condition of MAPbI<sub>3</sub> within the thermodynamically stable narrow chemical potential region. The chemical potential is corresponding to the energy of point defect formation. The dominant point defects in MAPbI<sub>3</sub> are  $MA_I$  and  $V_{Pb}$ . The chemical potential energy for the ion migration of MAPbI<sub>3</sub> can be calculated from the following set of Eq. 2.5 [30].

$$\left. \begin{aligned} \mu_{CH_3NH_3} + \mu_{Pb} + 3\mu_I &= \Delta H_S(CH_3NH_3PbI_3) = -5.26 \text{ eV} \\ \mu_{CH_3NH_3} + \mu_I &< \Delta H_S(CH_3NH_3I) = -2.87 \text{ eV} \\ \mu_{Pb} + 2\mu_I &< \Delta H_S(PbI_2) = -2.11 \text{ eV} \end{aligned} \right\} \quad (2.5)$$

The  $\text{MA}^+$  cation is non-centrosymmetric, and Yin et al. [30] also found that the total energy and electronic structure of  $\text{MAPbI}_3$  are fragile because of weak Van der Waals interaction between oriented non-centrosymmetric  $\text{MA}^+$  and 3-D Pb-I framework. Yin et al. [30] also reported the relationship between chemical potential ( $\mu$ ) of constituent elements and their defect formation enthalpy ( $\Delta H_s$ ). This study considered all possible point defects including three vacant sites ( $V'_{\text{MA}}, V''_{\text{Pb}}, V^\circ_{\text{I}}$ ), all interstitial ( $\text{MA}_i^\circ, \text{Pb}_i, \text{I}_i$ ), the substitution of cations ( $\text{MA}_{\text{Pb}}, \text{Pb}_{\text{MA}}$ ) and antisite substitutions ( $\text{MA}_{\text{I}}, \text{Pb}_{\text{I}}, \text{I}_{\text{MA}}, \text{I}_{\text{Pb}}$ ). These defects also contribute towards the conduction mechanism in halide perovskite, which is important to understand the unusual ionic conduction in perovskites. This study also revealed that an unusual behavior such as current–voltage hysteresis and dielectric response observed at low frequency is mainly due to the migration of ions, so halide perovskites are the mixed ionic-electronic conductors.

The defect formation energy is shown in the Table 1. The defects such as  $\text{MA}_i$ ,  $V_{\text{Pb}}$ ,  $\text{MA}_{\text{Pb}}$ ,  $\text{I}_i$ ,  $V_{\text{I}}$  and  $V_{\text{MA}}$  having formation energy less than  $\sim 0.5$  eV are observed near the valance band or the conduction band edge of  $\text{MAPbI}_3$ . Thus, these defects are observed to create only shallow level states in between the bandgap and other defects such as  $\text{I}_{\text{Pb}}$ ,  $\text{I}_{\text{MA}}$ ,  $\text{Pb}_i$ ,  $\text{Pb}_{\text{I}}$  having high formation energy, which creates deep defect level states. The defects such as  $V_{\text{Pb}}$  and  $\text{MA}_{\text{Pb}}$  are dominant vacancies for shallow level states, which originates from the antibonding states present at valance band maximum (VBM). The shallower nature of  $\text{MA}_i$  and  $V_{\text{I}}$  is observed mainly due to the high ionic nature of MA and Pb ions. The most common defects in  $\text{MAPbI}_3$  have been reported as *p*-type  $V_{\text{Pb}}$  and *n*-type  $\text{MA}_i$  which are mainly responsible for recombination and ionic conduction in  $\text{MAPbI}_3$ -based solar cells. This study indicated that the halide perovskites may not be in the pure perovskite phase, whereas the second phase may arise due to the formation of defects by the low formation energies. Impact of defects on solar cell performance parameters, the fundamental efficiency limitation of solar cell and efficiency limitation due to the presence of various recombination processes caused by the various defects in perovskite is already discussed in the previous section.

## 2.4 Factors effecting non-radiative recombination-shallow and deep level defects

Shallow level trap states are the states which lie very near to the conduction or valance band edge of the semiconductor. These states can be easily ionizable at room temperature and contribute towards conduction in semiconductors. One such example is of doped semiconductor, where acceptor or donor levels are shallow level states. According to SRH recombination model [14], these states do not contribute much towards the non-radiative recombination. Usually dangling bonds present due to surface termination cause deep level traps in the semiconductor. Since trap states below the intrinsic Fermi level of semiconductor are occupied with the free charge carriers. So due to the presence of large occupied trap states while forming a metal semiconductor contact, sometimes a thermal equilibrium condition can be established between the surface states of a semiconductor and metal contact of the solar cell. In such cases, the thermal equilibrium between the semiconductor band edges and metal contact is hindered, and this situation is also known as Fermi level pinning of the absorber layer of a solar cell. [35] The presence of deep level traps highly impacts the open circuit voltage of the solar cell because of ineffective quasi-Fermi splitting due to the presence of Fermi level pinning. Another example of deep lying states in perovskite-based solar cell is the diffusion of metal contact cation inside the active semiconductor layer. [36] In order to overcome these challenges, one has to detect, mitigate and passivate these deep level defect states present in the semiconductor bandgap. We have discussed various defect mitigation strategies of perovskite-based solar cell in the Sect. 5 of this review.

## 3 Defect identification and their influence on physical parameters of perovskite

### 3.1 Dark JV measurement

*JV* measurement of solar cell is a great tool for qualitatively determining the impact of defect recombination in the solar cell. Dark *JV* response of the solar is similar to solid-state diode and is given by Eq. 3.1 [37],  $J_{\text{rad}}$  is the radiative current density of the solar cell.

**Table 1** Defect formation energies (eV) of various point defects in  $\text{MAPbI}_3$  perovskite calculated using the first principle method [34]

Condition	$\text{I}_i$	$\text{MA}_{\text{Pb}}$	$V_{\text{MA}}$	$V_{\text{Pb}}$	$\text{I}_{\text{MA}}$	$\text{I}_{\text{Pb}}$	$\text{MA}_i$	$\text{Pb}_{\text{MA}}$	$V_{\text{I}}$	$\text{Pb}_i$	$\text{MA}_{\text{I}}$	$\text{Pb}_{\text{I}}$
Pb-rich/I-poor	0.23	0.28	0.81	0.29	1.96	1.53	1.39	2.93	1.87	4.24	3.31	5.54
Moderate	0.83	1.15	1.28	1.62	3.01	3.45	0.93	2.51	1.27	2.91	2.25	3.62
Pb-poor/I-rich	1.42	1.47	2.01	2.68	4.34	5.10	0.20	1.74	0.67	1.85	0.93	1.97



$$J_{rad}(V) = J_0 \left[ \exp\left(\frac{qV}{KT}\right) - 1 \right] \quad (3.1)$$

Due to the presence of other non-radiative recombination centers, the dark  $JV$  response of solar cell has to be modified by a factor as shown below in Eq. 3.2. [38]

$$J_{non-rad}(V) = J_0 \left[ \exp\left(\frac{qV}{nKT}\right) - 1 \right] \quad (3.2)$$

where  $n$  is known as diode quality factor. Slope of  $\ln(J)$  vs  $V$  (Eq. 3.3) [38] in the small voltage regime ( $V < V_{bi}$ ) can be used to estimate the diode quality factor. Figure 4b indicates the estimation of diode quality factor using the dark  $JV$  response of MAPbI<sub>3</sub>-based solar cell.

$$n = \left[ \left( \frac{KT}{q} \frac{\partial \ln(J)}{\partial V} \right) \right]^{-1} \quad (3.3)$$

By comparing Eqs. 3.1 and 3.2, it can be seen that the diode quality factor for radiative recombination mechanism is unity. Usually due to the presence of various non-radiative recombination centers, diode quality factor of a solar cell usually lies between 1 and 2. [38, 39] Whenever the value of diode quality factor is unity, then the transport in solar cell is of purely diffusive nature, and transport is limited by the space charge region. For diode quality factor value  $n > 1$ , transport is governed by both diffusion and drift of charge carriers. Depending upon the type of recombination, the radiative current of solar cell scale as  $J_{rad} \propto n^\alpha$  where diode quality factor  $n$  and  $\alpha$  related by the relation  $n = 2/\alpha$ ,

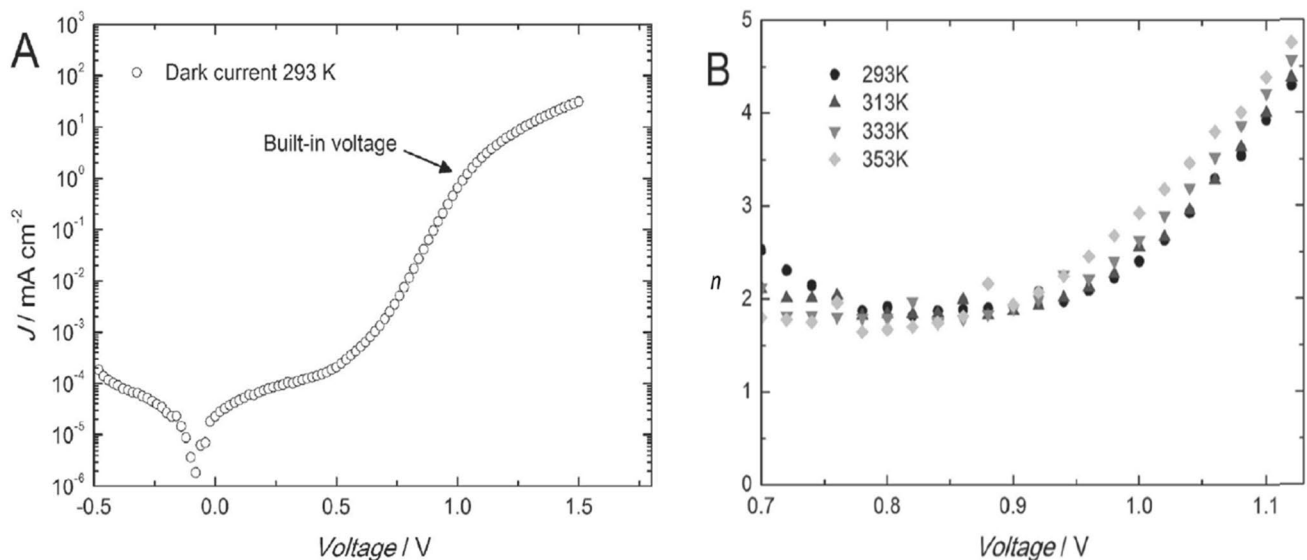
$\alpha = 1$  for pure non-radiative recombination, and  $\alpha = 2$  for the pure radiative recombination. [40]

### 3.2 CV profiling

Capacitance of  $p-n$  junction arises due to the diffusion of majority charge carriers from  $n$  to  $p$  side and  $p$  to  $n$  side of the junction because of the presence in diffusion gradient on both sides. Due to the diffusion of charge carriers,  $p-n$  junction becomes depleted of majority charge carrier (electron on  $n$  side of the semiconductor and holes on  $p$  side of the semiconductor), and this region of depletion is also known as space charge region of the diode and width of region is known as depletion width of the diode. Capacitance measurement of  $p-n$  junction is sensitive to charge carrier capture and emission due to the defect states present inside the bandgap. Small signal variation in differential capacitance ( $C = \frac{dq}{dV}$ ) can furnish the information about the orientation and influence of sub bandgap states on the non-radiative recombination in semiconductors. These signals mainly originated from space charge region near  $p-n$  junction of the diode. Under depletion approximation (abrupt boundaries and fully depleted space charge region), junction capacitance per unit area can be defined by Eq. 3.4 [17].

$$C = \frac{\epsilon \epsilon_0}{W} \quad (3.4)$$

where  $C$  is the capacitance of junction,  $\epsilon$  is dielectric constant,  $\epsilon_0$  is the permittivity of free space and  $W$  is the width of depletion region and given by Eq. 3.5 [17].



**Fig. 4** (a) Dark  $JV$  response of perovskite-based solar cell in the device stack (PCBM/MAPbI<sub>3</sub>/polyTPD/PEDOT:PSS/ITO/Substrate), (b) determination of temperature dependent diode quality factor by using Eq. 3.3 and using the plateau value of  $n$  vs  $V$  graph.

The obtained value of diode quality factor was between 1.7 and 1.8 indicating the presence of strong trap-assisted recombination in the device [38]

$$W = \sqrt{\frac{2\epsilon\epsilon_0(V_{bi} - V_{dc})}{eN_B}} \quad (3.5)$$

$N_B$  is the doping concentration,  $V_{bi}$  is the built-in voltage and  $V_{dc}$  is the DC component of applied voltage across the device. By substituting  $W$  and replacing  $N_B = N_{CV}$  (as  $N_{CV}$  is the CV density of states) into Eq. 3.4, the capacitance of junction as a function of applied voltage is given by the Mott-Schottky relation as shown below in Eq. 3.6 [41].

$$C^{-2} = \frac{2(V_{bi} - V_{dc})}{e\epsilon\epsilon_0 A^2 N_{CV}} \quad (3.6)$$

Using Eq. 3.6 in a linear scale plot of  $C^{-2}$  vs  $V$ , the intercept will yield the built-in voltage, and slope will give the estimation  $N_{CV}$  of the device. Under the applied periodic voltage trap states can modify the capacitance of  $p-n$  junction diode via modification of space charge density and influencing the depletion width of the diode. Secondly, since trap states are electrically charged, so in the response of external voltage these states can change their charge state behavior dynamically. In order to get response from trap states, the rate of electron capture or emission should be comparable to the input periodic applied voltage frequency ( $e_n \sim \omega$ ). In general, Eq. 3.4 [42] can be modified to the capacitance of the diode.

$$C = \frac{\epsilon\epsilon_0 A}{\langle x \rangle} \quad (3.7)$$

where  $\langle x \rangle$  is the first moment of charge response due to the presence of traps states in the device. [41] The CV response of the device is mainly used to estimate the doping profile, electric field profile, built-in voltage, dielectric constant and the interface quality of the  $p-n$  junction diode. [43, 44]

**Case studies** Using the CV spectroscopic measurements, Guerrero et al. [45] studied the degradation of perovskite solar cell in the device stack ITO/PEDOT:PSS/MAPbI<sub>3</sub>/PCBM/Metal by varying the metal electrodes as Ca, Ag, Au, Al, Cr<sub>2</sub>O<sub>3</sub>-Cr. Authors have observed device with Cr<sub>2</sub>O<sub>3</sub>-Cr (buffer layer) as a metal contact showed no S shape JV behavior after the device degradation under constant light illumination. Through CV measurement, authors have compared the bulk properties of perovskite devices before and after the light-induced degradation and concluded that bulk properties of perovskites were not modified significantly before and after the light degradation. But it is the surface states of perovskite/metal interface causing the high detrimental effects. Due to the light-induced dipoles caused by the high charge carrier accumulation region around the metal/perovskite interface, the S shape behavior was observed in the JV response

of the different devices. A buffer layer in-between perovskite and metal could prevent the light-induced dipoles at the metal/perovskite surface. The CV density of states and  $V_{bi}$  calculated using CV measurement techniques for some of the devices studied in the literature are listed below in Table 2.

### 3.3 Deep level transient spectroscopy (DLTS)

DLTS is a measurement of transient capacitance signal generated due to deep lying traps in response to the applied voltage or optical pulse (OD-DLTS). DLTS spectroscopy technique can be used to determine defect type, activation energy, trap concentration and various other parameters such as capture cross-sectional area, location of deep lying states. DLTS signal is calculated using the small change in capacitance value due to the small variation in trap containing charges at the immediate location away from the junction (at  $x=0$ ) in response to the applied input. The relative DLTS signal is given by Eq. 3.8. [41]

$$\frac{\Delta C}{C} = \frac{N_T \Delta x}{W^2} \left( \frac{x + W_n}{N^-} - \frac{W_p - x}{N^+} \right) \quad (3.8)$$

$N^-$  and  $N^+$  are the densities of the negatively and positively charged ionized traps on either side of the junction in response to the applied input on the device.  $N_T$  is the density of trap states, and  $\Delta x$  is the small positional variation of trap states away from the junction at  $x=0$ . Also,  $C$  is the imaginary part (Eq. 3.12) of admittance ( $Z$ ) of  $p-n$  junction, and it is given by Eq. 3.9. [41]

$$C = \text{Im}g \frac{(1/Z)}{\omega} \quad (3.9)$$

DLTS signal is measured using the probe signal (optical/electrical) on a reversed (forward) biased  $p-n$  junction. To observe the capacitance transient of a  $p-n$  junction using the DLTS spectroscopy since the  $p-n$  junction is reversed biased and immediately after the application of probe pulse, the depletion width of the junction is reduced from its reverse bias condition for a small pulse period of time  $\Delta t$ . Newly generated charge carrier due to the pulse signal is captured by the traps, and after a time  $\Delta t$  when the reverse bias condition of the junction is restored, trap captured minority carrier is swept away, but the captured majority carriers still remain trapped inside the defect states. This leads to a temporary decrease in the capacitance value because of an increase in the depletion width of a  $p-n$  junction due to the pulse signal. The small variation in capacitance  $\Delta C$  is observed as a capacitance transient of the device. Capacitance transition response of the junction is given by Eq. 3.10. [41, 51]

**Table 2** Determination of perovskite effective doping density of states ( $N_{CV}$ ) and built-in voltage ( $V_{bi}$ ) using CV spectroscopic technique

Device architecture	Effective doping density $N_{cv}$ ( $1/\text{cm}^3$ )	$V_{bi}$ (eV)	Reference
FTO/TiO <sub>2</sub> /MAPbI <sub>3-x</sub> Cl <sub>x</sub> /Spiro-OMeTAD/Au	$18 \times 10^{16}$	1.10	[44]
FTO/TiO <sub>2</sub> /MAPbI <sub>3-x</sub> Cl <sub>x</sub> /Au	$3.2 \times 10^{16}$	0.94	[44]
ITO/PEDOT:PSS/MAPbI <sub>3</sub> /PCBM/Metal	$1 \times 10^{16}$	1.10	[45]
ITO/PEDOT:PSS/MA(PbI <sub>2</sub> ) <sub>1-x</sub> (CuBr <sub>2</sub> ) <sub>x</sub> /PCBM/LiF/Al, for $X=0.1$	$9.28 \times 10^{16}$	-	[43]
Au/BCP/PCBM/MAPbI <sub>3</sub> /PEDOT:PSS/FTO	$6.93 \times 10^{14}$	-	[43]
FTO/TiO <sub>2</sub> /Perovskite/P3HT/Au	$3 \times 10^{16}$	-	[46]
FTO/c-TiO <sub>2</sub> /m-TiO <sub>2</sub> /MAPbI <sub>3</sub> /Spiro-OMeTAD/Au	$1.4 \times 10^{18}$	1.2	[47]
FTO/c-TiO <sub>2</sub> /MAPbI <sub>3</sub> /Spiro-OMeTAD/Au	$2.4 \times 10^{17}$	1.2	[47]
FTO/PCBM/C <sub>60</sub> /MAPbI <sub>3</sub> /PTAA/BCP/Au	$2.8 \times 10^{16}$	1.0	[48]
FTO/PCBM/C <sub>60</sub> /FAPbI <sub>3</sub> /PTAA/BCP/Au	$2.5 \times 10^{16}$	1.3	[48]
FTO/MAPbI <sub>3</sub> /Au	$2.7 \times 10^{14}$	-	[49]
FTO/c-TiO <sub>2</sub> /m-TiO <sub>2</sub> /MAPbI <sub>3</sub> /Spiro-OMeTAD/Au	$(1.37 \times 10^{17})_{\text{peak}}$	0.69	[49]
FTO/c-TiO <sub>2</sub> /m-TiO <sub>2</sub> /(MAPbI <sub>3</sub> ) <sub>0.85</sub> (FAPbBr <sub>3</sub> ) <sub>0.15</sub> /Spiro-OMeTAD/Au	$(8.84 \times 10^{16})_{\text{peak}}$	1.05	[49]
FTO/b-TiO <sub>2</sub> /m-TiO <sub>2</sub> /MAPbI <sub>3</sub> /Spiro-OMeTAD/Au	$6.08 \times 10^{17}$	0.75	[50]
FTO/b-TiO <sub>2</sub> /m-TiO <sub>2</sub> /MAPbI <sub>3</sub> /MIC2/Spiro-OMeTAD/Au MIC2 = <i>N</i> -methyl thiazolium iodide	$1 \times 10^{17}$		[50]
FTO/b-TiO <sub>2</sub> /m-TiO <sub>2</sub> /MAPbI <sub>3</sub> /MIC3/Spiro-OMeTAD/Au MIC3 = 3,4-dimethyl thiazolium iodide	$7.54 \times 10^{17}$	1.18	[50]
FTO/b-TiO <sub>2</sub> /m-TiO <sub>2</sub> /MAPbI <sub>3</sub> /MIC4/Spiro-OMeTAD/Au MIC4 = 3,4,5-trimethyl thiazolium iodide	$6.08 \times 10^{17}$	1.14	[50]

$$C(t) = C_{\infty} \left( 1 \mp \frac{N_T}{2N^-} \exp(-e_i t) \right) \quad (3.10)$$

$C_{\infty}$  is the steady-state capacitance of the  $p$ - $n$  junction and  $e_i$  is the rate of trap capture coefficient by the defect states. The positive sign indicates enhancement in the capacitance, and negative sign indicates decrease in the capacitance value. Capacitance value changes due to the response of trap states before and after the application of input pulse. Rate window for the DLTS signal measurement is defined by Eq. 3.11. [41]

$$\tau = \frac{\tau_1 - \tau_2}{\ln(t_1/t_2)} \quad (3.11)$$

The probing frequency for DLTS is chosen such that  $f = \frac{1}{2\pi\tau}$ .

**Case studies** Heo et al. [52] studied the DLTS spectroscopy on single step deposited and double step deposited device based on the MAPbI<sub>3</sub> perovskite. Authors have observed two signature defect peaks at the energy location  $E_1$  and  $E_2$  in both devices, but the single step deposited film is observed to be having higher defect density than the double step deposited sample (Table 3). Based on the first principle calculation performed previously [34], authors have assigned 0.60 and 0.75 trap states as substitutional vacancies

of  $I_{Pb}$  and  $I_{MA}$ . Due to the large defect density in single step deposited device, its Fermi level is likely to be pinned at the center. Polyakov et al. [53] studied mixed cation perovskite  $\text{Cs}_x(\text{MA}_{0.17}\text{FA}_{0.83})_{(1-x)}\text{Pb}(\text{I}_{0.83}\text{Br}_{0.17})_3$  using the DLTS spectroscopy and discovered a donor defect energy level just below the conduction band and two other semi deep trap levels (Fig. 5a). In Table 3, we have listed few of the DLTS measurement studies alongside the commonly observed defect location with the trap density observed in various 3D halide perovskites. Understanding and reduction of these detrimental trap levels are highly important for the  $V_{OC}$  and  $J_{SC}$  enhancement of the perovskite solar cell.

Heish et al. [54] studied the impact of intermolecular and interfacial defect density of the perovskite device by considering the three different hole transport layer (HTL) such as P3HT, PBTTTV-h and spiro-OMeTAD. Authors have observed lower defect density in PBTTTV-h and spiro-OMeTAD based device because of the better band edge alignment at the PBTTTV-h/perovskite and spiro-OMeTAD/perovskite interface compared to P3HT/perovskite interface. Xue et al. [55] also studied charge-based DLTS spectroscopy (Q-DLTS) on MAPbI<sub>3</sub>-based solar cell. Q-DLTS signal was observed to be strongly polarity dependent indicating majority of the defects were present near the perovskite and charge transfer layer interface only.

**Table 3** Literature review of defect parameters such as location of defect level energy (eV), type of defects and defect density/cm<sup>3</sup> of various perovskite-based semiconductor measured using DLTS and TAS spectroscopy. Location of defect energy levels and defect density is highly correlated with the device fabrication conditions so these parameter values are only indicative in nature

Perovskite material	Defect level location (eV)/type	Defect density/cm <sup>3</sup>	Reference
MAPbI <sub>3</sub>	One step 0.62, 0.75 Two steps 0.62, 0.76	$1.3 \times 10^{15}$ , $3.9 \times 10^{14}$ $5 \times 10^{14}$ , $9.5 \times 10^{14}$	[52]
Cs <sub>x</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>(1-x)</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub>	0.57 (hole), 0.74 (electron) 0.2 (donor)	Donor level = $10^{18}$ Hole = $0.12 \times 10^{14}$ Electron = $2 \times 10^{14}$	[53]
MAPbI <sub>3</sub>	0.324 0.46	$\sim 10^{17}$	[58]
MAPbBr <sub>3</sub> single crystal	0.17 0.20	$\sim 10^8$ $\sim 10^9$	[59]
FAPbI <sub>3</sub> (mixed with MAPbBr <sub>3</sub> )	0.46 0.72 0.86	-	[60]
MAPbI <sub>3</sub>	0.16 (acceptor)	$10^{16}$	[61]
MAPbI <sub>3</sub>	0.12, 0.52, 1.42		[62]
MAPbI <sub>2</sub> Br	0.45, 1.03	$\sim 10^{16}$ – $10^{17}$	
MAPbI <sub>2</sub> Cl	1.25, 0.07		
MAPbI <sub>3</sub>	0.22, 0.32, 0.40, 0.49, 0.51	$10^{17}$	[55]
MAPbI <sub>3</sub>	$\delta=0.19$ $\beta=0.37$ $\gamma=0.37$	$\sim 10^{13}$ – $10^{14}$	[51]

Authors have discovered a distribution of defect energy level  $E_T$  centered around 0.45 eV having the highest trap density. Reichert et al. [51] studied temperature dependence of DLTS signal on MAPbI<sub>3</sub>-based solar cell. They characterized the ionic defect distribution in archetypal perovskite (Fig. 5b). As predicted from the previous studies and first principle calculation [34], point defect vacancies such as  $V_I^-$ ,  $V_{MA}^-$ ,  $I_i^-$ ,  $MA_i^+$  ( $i$  stands for the interstitial vacancies) are supposed to dominate the ionic migration in perovskite material. Another work by Reichert et al. [56] has studied the ionic defect distribution by gradually varying the stoichiometry of MAPbI<sub>3</sub> from the under-stoichiometric condition to the over-stoichiometric condition using the method previously proposed by Futscher et al. [57] The investigation established  $V_I^-$  vacancies in lower

stoichiometry, and interstitial vacancies such as  $I_i^-$ ,  $MA_i^+$  for over-stoichiometry films were dominating the ionic migration in MAPbI<sub>3</sub> perovskite.

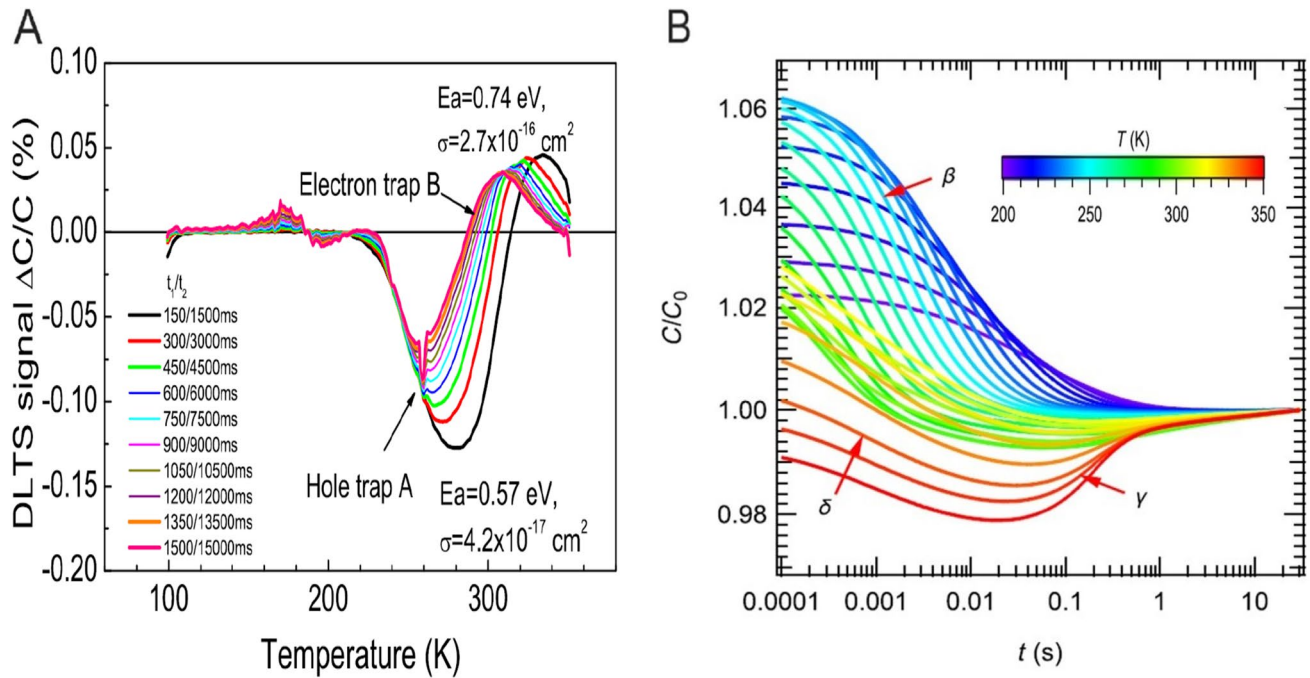
### 3.4 Thermal admittance spectroscopy (TAS)

TAS is yet another powerful technique for the determination of defect type, capture cross section and defect concentration [63]. TAS measures the admittance AS ( $f$ ,  $T$ ) of the  $p$ – $n$  junction with respect to the simultaneous variation in frequency as well as change in the temperature of the device. The admittance of  $p$ – $n$  junction is defined as described below in Eq. 3.12. [42]

$$Y(\omega, T) = G(\omega, T) + i\omega C(\omega, T) \quad (3.12)$$

**Table 4** Values of radiative rate constants and charge carrier mobility in different perovskite-based semiconductors where  $K_1$  = monomolecular recombination rate constant (s<sup>-1</sup>),  $K_2$  = bimolecular recombination rate constant (cm<sup>3</sup>·s<sup>-1</sup>),  $K_3$  = Auger recombination rate constant (cm<sup>6</sup>·s<sup>-1</sup>) and  $\mu$  = charge carrier mobility value respectively. Ref. = Reference

Material	$K_1$ (s) <sup>-1</sup>	$K_2$ (cm <sup>3</sup> ·s <sup>-1</sup> )	$K_3$ (cm <sup>6</sup> ·s <sup>-1</sup> )	$\mu = \mu_e + \mu_h$ (cm <sup>2</sup> /V·s) Ref
Perovskite thin films	Ref	Ref	Ref	
MAPbI <sub>3</sub>	$1.5 \times 10^7$ [113] $1.8 \times 10^7$ [73] $7.27 \times 10^7$ [114]	$9.4 \times 10^{-10}$ [113] $1.7 \times 10^{-10}$ [73] $15 \times 10^{-10}$ [114]	$3.7 \times 10^{-29}$ [113] $13.5 \times 10^{-28}$ [114]	8.1 [113] 35 [115]
MAPbBr <sub>3</sub>	$2.72 \times 10^7$ [114]	$4.9 \times 10^{-10}$ [114]	$3.4 \times 10^{-28}$ [114]	17.6 [116]
MAPbI <sub>3-x</sub> Cl <sub>x</sub>	$0.4 \times 10^7$ [113] $1.2 \times 10^7$ [117]	$8.7 \times 10^{-11}$ [113] $1.1 \times 10^{-10}$ [117]	$9.9 \times 10^{-29}$ [113] $2.3 \times 10^{-29}$ [117]	11.6 [118] 33 [117] 40 [74] 27 [97]
FAPbBr <sub>3</sub>	$21 \times 10^6$ [117]	$11 \times 10^{-10}$ [117]	$1.5 \times 10^{-28}$ [117]	14 [117]
FAPbI <sub>3</sub>	$7 \times 10^6$ [117]	$1.1 \times 10^{-10}$ [117]	$0.2 \times 10^{-28}$ [117]	27 [117]
MASnI <sub>3</sub>	$8 \times 10^9$ [119]	$1.4 \times 10^{-10}$ [119]		1.6 [119]
FA <sub>x</sub> Cs <sub>1-x</sub> PbI <sub>3</sub>		$1 \times 10^{-10}$ [21]	$2.1 \times 10^{-27}$ [21]	20 [120]



**Fig. 5** (a) DLTS spectrum of multi-cation perovskite-based solar cell at various rate windows. The negative peak in the spectrum corresponds to the hole capture defect level, and the positive peak corresponds to the electron capture defect level [53], (b) determination of

defect migration in archetypal MAPbI<sub>3</sub> perovskite using DLTS measurement. The  $\delta$  peak was assigned to iodine migration to interstitial site, the  $\beta$  peak was assigned to the MA vacant site, while the  $\gamma$  peak was assigned to the presence of MA<sup>+</sup> at the interstitial site. [51]

where  $\omega$  is the probe frequency,  $G$  is the conductance and  $C$  is the capacitance of  $p$ – $n$  junction. The conductance of the  $p$ – $n$  junction is defined by using Eq. 3.13. [63]

$$\frac{G}{\omega} = \Delta C \left( \frac{\omega \tau}{1 + \omega^2 \tau^2} \right) \quad (3.13)$$

Since non-radiative recombination is a thermally activated process, the temperature dependence of emission rate due to the traps is given by Eq. 3.14. [51]

$$e_t = \frac{e^2 N_{\text{eff}} D_0}{K T \epsilon_0 \epsilon_r} \exp \left( -\frac{E_A}{K T} \right) \quad (3.14)$$

where  $N_{\text{eff}}$  is the effective doping density,  $D_0$  and  $E_A$  are the diffusion coefficient and the activation energy of the trap states respectively. Emission rate is determined by the gap window rate as described in Eq. 3.11. The characteristic frequency of charge carrier response is related to the dielectric relaxation time of the semiconductor, and it is given by Eq. 3.15. [42]

$$\omega_d = \frac{2\pi}{\tau_d} = \frac{\sigma}{\epsilon} \quad (3.15)$$

For the input frequencies higher than the characteristic carrier frequency  $\omega_d$ , free charge carriers are frozen out inside the semiconductor, and it behaves like a

dielectric material. [42] Capacitance of a  $p$ – $n$  junction under freezeout condition is given by Eq. 3.16 [42] and also known as geometric capacitance of the diode.

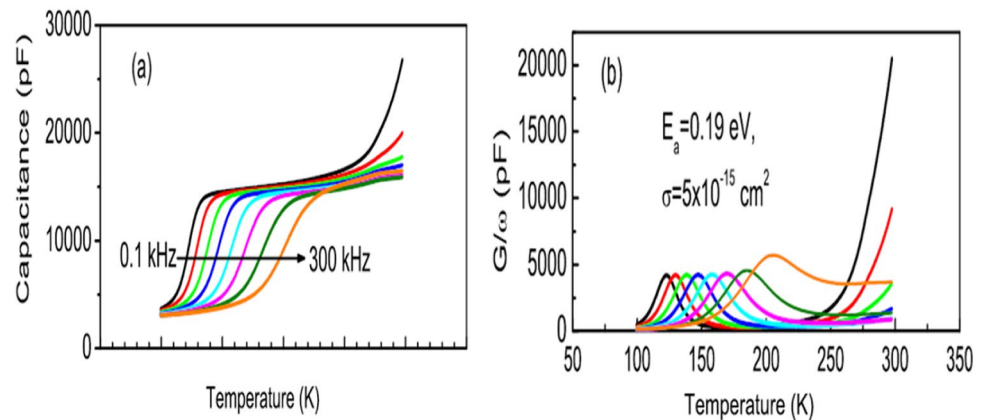
$$C = \frac{\epsilon \epsilon_0}{d} \quad (3.16)$$

where  $d$  is the distance between two electrodes of the device. In order to activate response from the deep lying states, one has to increase the temperature of the device or tune frequency of the input signal in the frequency range comparable to emission rate of charge carrier from the trap states. At much higher frequency  $\omega \gg e_n, e_p$  transport in semiconductor is limited only by the free charge carrier-based mobility so TAS can also be used to measure charge carrier mobilities as well. [64, 65]

**Case studies** TAS study performed on multi-cation based perovskite by Polyakov et al. is shown below in Fig. 6a, b. [53] They observed a strong freezeout capacitance region and a peak in capacitance below the temperature 250 K as shown in Fig. 6a. They also observed a capacitance and conductance peak shift with increase in the probe frequency. The abrupt increase in the capacitance above temperature 250 K was observed due to the presence of parasitic capacitance of the device. This study also indicates that above 250 K defects does not contribute towards change in the



**Fig. 6** (a) Measurement of capacitance versus change in temperature at various frequencies using the thermal admittance spectroscopy. (b) Measurement of AC conductance versus temperature at different frequencies using thermal admittance spectroscopy for the multi cation based  $\text{Cs}_x(\text{MA}_{0.17}\text{FA}_{0.83})_{1-x}\text{Pb}(\text{I}_{0.83}\text{Br}_{0.17})_3$  perovskite solar cell. [53]



TAS signal. One of the important applications of TAS is the measurement of trap density of states (tDOS) [66], and it is given by Eq. 3.17. [67]

$$N_T(E_\omega) = -\frac{V_{bi}}{qW} \frac{dC}{d\omega} \frac{\omega}{KT} \quad (3.17)$$

Xiao et al. [66] used this relation to calculate tDOS for MAPbI<sub>3</sub>-based solar cell for two different cases, thermal annealed sample and DMF solvent (vapor) annealed perovskite film. The tDOS for thermal annealed device was found to be  $1.8 \times 10^{16}/\text{cm}^3$ , and tDOS for the solvent annealed device was found to be  $5.3 \times 10^{16}/\text{cm}^3$ . The tDOS for the solvent annealed device was observed to be 16 times smaller than the thermal annealed device. Hence, solvent annealed device was observed to be better performing than the thermal annealed device; hence, tDOS measurement can also be taken as a direct indicator for better performing device. Wu et al. [68] distinguished surface and bulk defect in the 5 different device of stacks FTO/TiO<sub>2</sub>/perovskite/Spiro-OMeTAD-Au(device1), FTO/TiO<sub>2</sub>/PCBA(monolayer)/perovskite/SpiroOMeTAD/Au(device2), FTO/perovskite/Spiro-Au (device3), FTO/TiO<sub>2</sub>/perovskite/Au (device 4), FTO/TiO<sub>2</sub>/PCBA/perovskite/Au (device 5). Through TAS measurement, authors have calculated the bulk as well as surface defect density by using the relation  $C = qAN_{ss}$  where  $N_{ss}$  is the surface defect density states of the perovskite/contact interface. All the different devices showed similar bulk capacitance response indicating same bulk defect density in the range of  $10^{17}/\text{cm}^3$  to  $10^{18}/\text{cm}^3$ . This implies that different interface configuration as in different devices from 1 to 5 does not influence the bulk defect density of the perovskite layer. But the calculated interface defect density was found to be different for each case, and the interface defect density was observed to be increasing with the removal of ETL and HTL layers. Authors have attributed change in different device PCE and device degradation

to change in the interface defect density. Awni et al. [69] argued that high-frequency capacitance response of charge carrier in perovskite-based solar cell is due to the charge carrier response of the charges present inside the HTL material. Hence, high-frequency capacitance measurement cannot be taken as a reliable measurement technique for defect distribution in perovskite. Though high-frequency response of perovskite solar cell without HTM layer can be used to calculate bulk perovskite defect properties. However, low-frequency response of the charge carriers can still be used as a reliable method for measurement of defect activation energy. Cho et al. [70] also highlighted the importance of perovskite/charge transfer layer interface. Author has studied Cs-doped thin film under PbI<sub>2</sub>-rich and PbI<sub>2</sub>-deficient condition by varying the PbI<sub>2</sub> molar concentration in device stack ITO/SnO<sub>2</sub>/(FA<sub>0.9</sub>MA<sub>0.1</sub>)Pb(I<sub>x</sub>Br<sub>1-x</sub>)/Spiro-OMeTAD. Through tDOS and photo-aging measurements, Pb-rich device was observed to be prone to the formation of deep level defects and irreversible degradation. Authors have assigned this irreversible degradation to Pb-I antisite formation and un-coordinated Pb creating deep donor like defect levels. Balance stoichiometric and Pb-deficient device was observed to be more stable due to surface passivation of Pb-I antisite defects.

### 3.5 Radiative recombination and photoluminescence (PL) spectroscopy

Photoluminescence signal is generated due to radiative recombination of photogenerated  $e-h$ , and emitted photons are detected outside to construct a photoluminescent signal. The spontaneous rate of emission at thermal equilibrium is given by Eq. 3.18. [12]

$$R_{SP}^0 = \frac{8\pi n_r^2}{h^3 c^2} \frac{\alpha(E)E^2}{\exp(E/KT) - 1} \quad (3.18)$$

Using Eq. 3.18, the rate of spontaneous emission after an excitation source is given by Eq. 3.19. [12]

$$R_{SP} = R_{SP}^0 \frac{np}{n_0 p_0} - R_{SP}^0 = K_2 n_i^2 \left( \exp\left(\frac{\Delta\mu}{KT}\right) - 1 \right) \quad (3.19)$$

The photoluminescence yield generated due to emission of photons is given by Eq. 3.20. [12]

$$Y_{PL}(E) = \frac{1}{4\pi^2 h^3 C^2} \frac{\alpha(E) E^2}{\exp\left(\frac{E-\Delta\mu}{KT}\right) - 1} \quad (3.20)$$

Finally, the photoluminescence efficiency is given by Eq. 3.21 [20], and it is the ratio of radiative recombination divided by the total recombination rate happening inside the semiconductor material.

$$\phi(n)_{PL} = \frac{nK_2}{K_1 + nK_2 + n^2K_3} \quad (3.21)$$

Photoluminescence yield in perovskite semiconductor is found to be increasing with an increase in the excitation intensity which is a great signature of perovskite being a direct bandgap semiconductor. [71, 72] Further, large PL intensity due to the radiative recombination in perovskite also suggests transport in perovskite is dominated by the free charge carrier rather than the excitonic charge transport. Yamada et al. [73] studied the photoluminescence spectrum in MAPbI<sub>3</sub> thin film deposited on mesoporous TiO<sub>2</sub> by varying the different excitation fluence as shown below in Fig. 7.

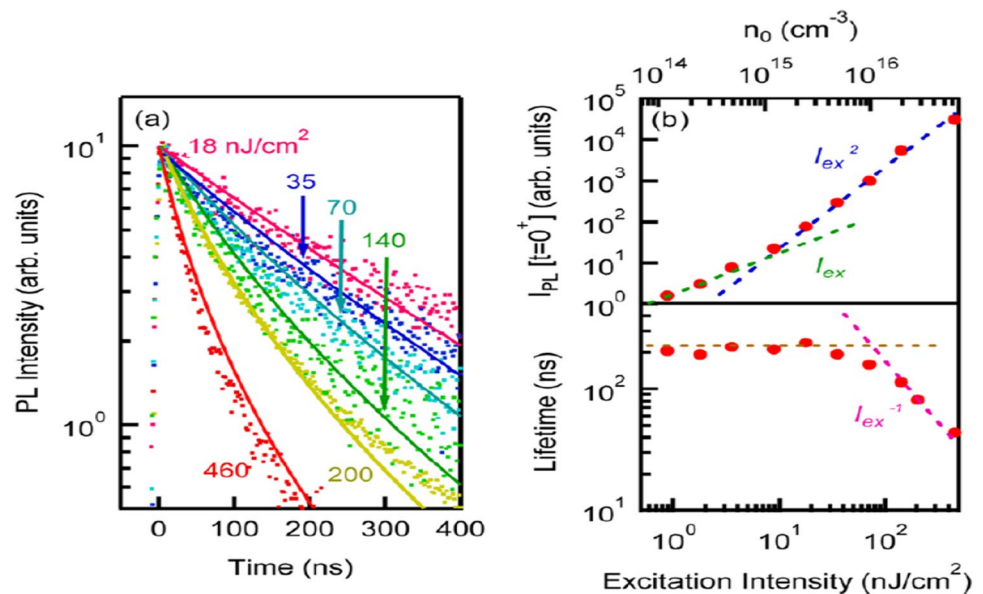
At lower excitation intensity, the PL showed a monoexponential decay because at the lower excitation levels only the non-radiative recombination channel is activated. The PL decay time in such case is the non-radiative lifetime of the

semiconducting material. At higher excitation intensity, mono-exponential decay changes into faster non-exponential decay because of the activation of bimolecular and Auger recombination processes respectively. By observing Fig. 7b, charge carrier lifetime measured from the PL spectroscopy initially stays constant upon changing the excitation intensity and after a certain excitation limits a nonlinear dependence of charge carrier lifetime due to the presence of higher order recombination can be observed. Also, the PL intensity is observed to be increasing linearly, and after a certain limit the quadratic dependence is observed due to the bimolecular recombination processes present in the perovskite semiconductor. The effective PL lifetime at large photon excitation intensity is given by Eq. 3.22. [73] Fig. 8a depicts the observed behavior of different charge carrier lifetime measured using the PL spectrum as a function excess charge carrier density.

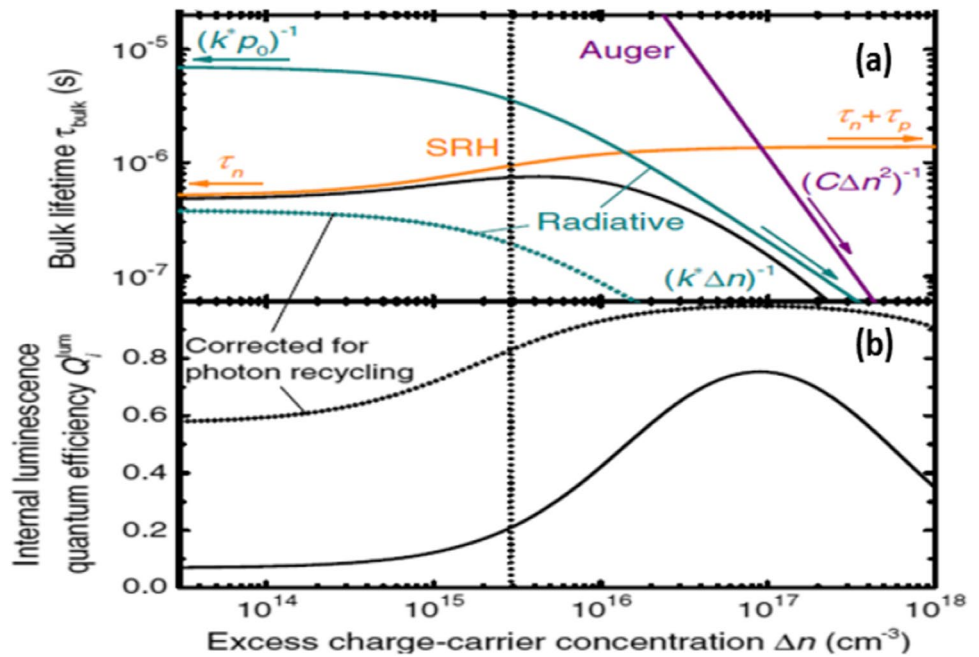
$$\tau_{tot|PL} = \frac{1}{K_1 + K_2 n + K_3 n^2} \quad (3.22)$$

**Case studies** Barugkin et al. [72] studied the temperature dependence of radiative recombination of MAPbI<sub>3</sub> thin film using the PL spectroscopy. The PL peak was observed to be red shifting with a decrease in the temperature. Authors described this behavior to the localization of charge carriers near the conduction and valence band edge due to the decrease in the temperature. The  $K_2$  was also observed to increase with the decrease in temperature which is a characteristic feature of a direct bandgap semiconductor. Light absorption coefficient of direct bandgap semiconductor is observed to first increase with increasing in the incident photon energy and become constant towards the high energy wing of the solar spectrum. For the low energy wing,

**Fig. 7** (a) Photoluminescence measurement of MAPbI<sub>3</sub> perovskite at different photoexcitation intensities, at higher intensity photo decay is much faster compared to lower intensities. (b) Variation of photoluminescence intensity with the photo-excitation intensity. The rate of charge carrier decay is linear in the low fluence regime (~non-radiative recombination regime) quadratic in the mid fluence regime (~radiative recombination regime) and charge carrier lifetime versus the variation in the excitation intensity of the source determined from the PL decay profile [73]



**Fig. 8** (a) Variation in the charge carriers lifetime of different recombination processes as of function of excess charge carrier concentration. (b) Increase in the internal quantum luminescence efficiency due to photo recycling effect as discussed in Sect. 4 of the review [74]



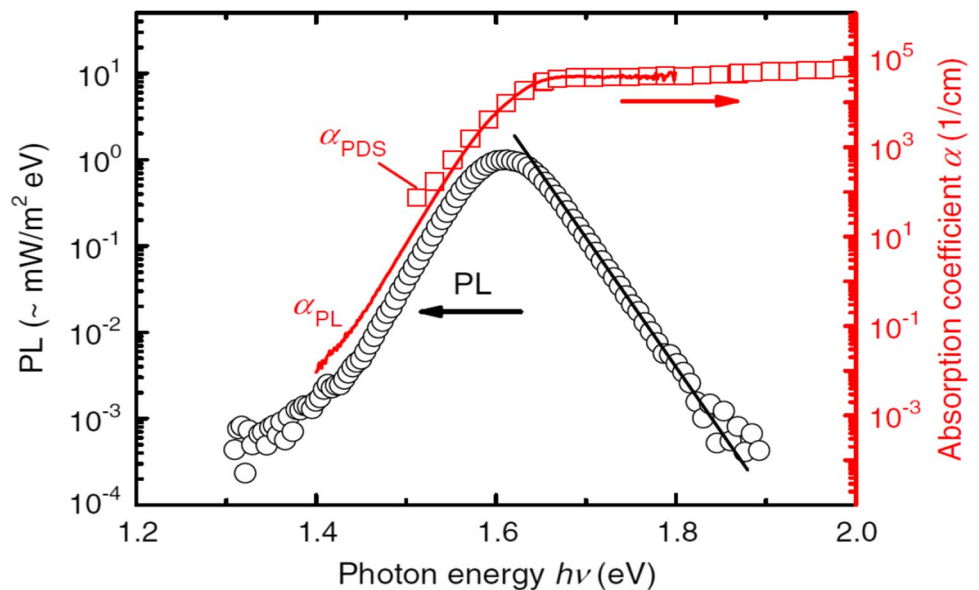
absorption of a semiconductor can be defined by the relation  $A = \alpha(E)d$ , and the PL yield is observed to increase monotonically with increase in the photon energy (Fig. 9). At the high energy wing of the PL spectrum, by assuming  $\alpha = 1$ , i.e. a uniform absorption of all photon with different energy and exploiting this behavior of light absorption coefficient of semiconductor into Eq. 3.20 and by rearranging it as Eq. 3.23. [12]

$$\ln\left(\frac{Y_{PL}(E)}{10^{23} E^2 / \text{cm}^2 \text{eV} - s}\right) = -\left(\frac{E - \Delta\mu}{KT}\right) \quad (3.23)$$

By plotting Eq. 3.23 and estimating the slope at high energy wing of PL spectrum, the operating temperature of device can be easily determined and the intercept on Y axis at  $E=0$  will yield the quasi-Fermi level separation of the solar cell [74, 75]. For high photon energy wing, the photoluminescence yield scales as  $Y_{PL}(E) \propto E^2 \exp(-E/KT)$ . This situation to estimate the quasi-Fermi level separation and device operating temperature using  $Y_{PL}$  is shown below Fig. 9.

Large PL yield is also a quality indicator for a solar cell for obtaining a large  $V_{OC}$ . [76] Using the inverse optical reciprocity relation, light absorption coefficient can also be

**Fig. 9** Determination of quasi Fermi level separation and device operating temperature containing the perovskite absorber using the photoluminescence experiment in the high energy wing of the photon spectrum where light absorption coefficient remains constant [74]



constructed using the PL spectrum. [72] Low temperature PL measurement is also performed to explore the excitonic features in the perovskite material. [77]

### 3.6 Radiative recombination and electroluminescence (EL) spectroscopy

Electroluminescence spectroscopy is the inverse of photovoltaics process; it is the emission of light due to radiative recombination promoted due to the application of external voltage. The electroluminescence efficiency of solar cell is the ratio of radiative current to the total injected current inside the device and given by Eq. 3.24. [74, 78]

$$(EQE)_{EL} = \tau_{eff}/\tau_R = \frac{(K_1n + K_2n^2 + K_3n^3)}{(K_2n^2)} \text{ or } (EQE)_{EL} = \frac{J_{rad}}{J_{inj}} \quad (3.24)$$

Under the radiative limit of the solar cell,  $(EQE)_{EL}$  must be equal to unity. The non-radiative  $V_{OC}$  is given by Eq. 3.25. [79]

$$V_{OC} = V_{OC}^{rad} + \frac{KT}{q} \ln(EQE)_{EL} \quad (3.25)$$

A reduction in the  $(EQE)_{EL}$  by a factor of 10 due to non-radiative recombination will reduce the  $V_{OC}$  by a magnitude of 60 mV. Okano et al. [80] studied the degradation mechanism of MAPbI<sub>3</sub>-based solar cell by means of EL and PL imaging techniques. Though spatial distribution of EL was observed identical before and after the device degradation, but the decrease in the EL intensity with time and its temporal evolution was assigned to degradation of the perovskite layer. The photoluminescence efficiency ( $\phi(n)_{PL}$ ) discussed earlier is the indicator for determining the departure of the  $V_{OC}$  of a solar cell from its radiative limit. A 100% photoluminescence efficiency indicates  $V_{OC} = (V_{OC})_{Rad}$  which is also the maximum voltage that can be extracted from a solar cell. High quality ionic crystalline materials such as GaAs-based solar cell are proven to have as high as 99.7% photoluminescence efficiency [81], while commercialized silicon-based solar cells have photoluminescence efficiency up to 20% even in state-of-the-art based devices. [82] This indicates that, it is difficult to obtain high  $V_{OC}$  from the silicon-based solar cell (close its radiative limit of the open circuit voltage).

In case of perovskite-based solar cells, through surface passivation effect, Braly et al. [83] managed to obtain a very high photoluminescence efficiency ~ 92%. By introducing the *n*-trioctylphosphine oxide (TOPO) on the surface of MAPbI<sub>3</sub> perovskite, authors have managed to obtain a  $V_{OC}$  of 1.28 V which is 97.1% of the radiative limit of MAPbI<sub>3</sub>-based absorber. Hameiri et al. [84] studied fast

camera-based PL and EL imaging on perovskite-based solar cell. Further, the correlation between the intensity of luminescence signal and  $V_{OC}$  of the solar cell has been explored via understanding the exponential relationship between quasi-Fermi level separation of the absorber layer with the photoluminescence intensity to determine  $V_{OC}$  of the solar cell. [85] Time resolved photoluminescence (TRPL) spectroscopy is a widely used technique [4, 86–88] to determine the efficient charge extraction at the ETL/perovskite and HTL/perovskite interface. The rapid quenching of PL signal away from open circuit voltage condition of the solar cell is regarded as a quality measure of the efficient charge carrier extraction at the charge selective and absorber layer interfaces. [89] Baloch et al. [16] studied the photocarrier dynamics at the HTL/perovskite interface by using the TRPL and also performed sensitivity analysis of various parameters such as surface recombination velocity ( $S_L$ ), interface recombination velocity ( $S_R$ ), charge carrier mobility ( $\mu$ ) and doping density ( $N_D$ ) by modeling the PL decay profiles. Usually, the PL signal is measured at the open circuit voltage condition of the solar cell since the radiative recombination at  $V_{OC}$  condition is the maximum. But Stolterfoht et al. [90] also measured PL signal as a function of voltage denoted by the symbol PL(V) on the perovskite-based solar cell by varying the HTL thickness and doping concentration. The PL(V) signal was observed to mirror the *JV* response of the solar cell in the power generating regime, and this also highlighted the correlation between the losses related to the non-radiative recombination process and radiative recombination process. High fill factor (FF)-based devices showed a rapid quenching of PL(V) while moving away from the open circuit voltage to the maximum power point condition of the solar cell. Authors have concluded that PL signal has to be maximized at open circuit voltage condition for obtaining the high efficiency solar cell. Rai et al. [91] studied the effect of perovskite absorber layer thickness on the  $(EQE)_{EL}$ . Thin perovskite layer was observed to show high  $(EQE)_{EL}$  in comparison to the thick perovskite layer because of requirement of the small injection current for the thinner samples. Perovskite-based semiconductors have also found widespread application in light emitting diodes (LEDs), and various researchers have studied the radiative recombination mechanism in perovskite for LED application by the means of EL and PL spectroscopy techniques. [92–95] Kirchartz et al. [96] also prepared a detailed study on the fundamentals of radiative recombination and its relation with EL and PL spectroscopy techniques.

### 3.7 Charge carrier mobility and diffusion length

The dc conductivity of a semiconductor is given by the relation  $\sigma = ne\mu$  where  $\mu$  is the mobility of free charge carriers. It has been observed that the mobility in typical



cubic perovskite varies as  $T^{-1.5}$  where  $T$  is the temperature of the device [97]. This indicated the phonon scattering influence on the mobility of charge carriers. [98] Perovskite thin films are highly defect tolerance despite having the presence of a large number of point defects ( $10^{17}/\text{cm}^3$ ). The reason behind this is the large formation energy of deep level states which can directly impact the mobility of charge carriers as discussed earlier. Charge carrier diffusion length can be calculated using the relation  $L_D = \sqrt{D\tau}$ ,  $D$  is the diffusion coefficient of charge carrier and related to the mobility by the Einstein relation as shown below in Eq. 3.26. [37]

$$D = \frac{\mu KT}{q} \quad (3.26)$$

Diffusion length is the maximum length of charge carriers which they can travel before recombining inside the material. Mobility in disordered semiconductor (organic semiconductor, a-Si) follows Langevin limit of the recombination. [99] In Langevin limit by assuming a hole in the semiconductor material forms a Coulomb potential well around an electron, and the probability of recombining  $e-h$  radiatively is decided by equilibrium between thermal energy and the potential energy of hole and electron charge assembly as described below in Eq. 3.27. [20]

$$KT = \frac{q^2}{4\pi\epsilon_r\epsilon_0 r} \quad (3.27)$$

Since the potential energy of the charge carrier is the derivative of electric field ( $E$ ) and by using the Ohms law relation  $J=q\mu E$ , the Langevin limit of recombination is given by Eq. 3.28. [99]

$$\frac{K_2}{\mu} = \frac{q}{\epsilon_r\epsilon_0} \quad (3.28)$$

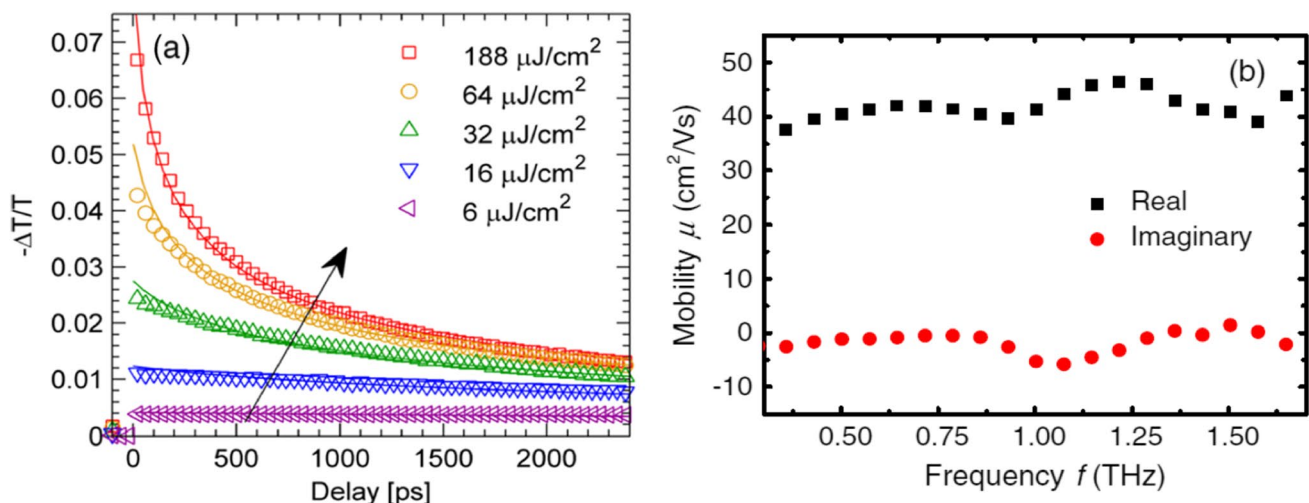
Perovskite-based semiconductors are observed to defy the Langevin limit (Eq. 3.28) by 4 to 5 orders of the magnitude; hence, charge carrier mobility in a perovskite semiconductor is limited only due to the phonon-electron scattering [99]. The reason behind this is the defect tolerance nature of perovskite absorbers, and this makes this material highly suitable for the optoelectronic applications. [29] Mobility and the diffusion length in perovskite-based semiconductor can be measured using various characterization techniques. We have listed one of the most prominent experimental techniques to measure charge mobilities using transient terahertz absorption spectroscopy (Fig. 10).

### 3.8 Terahertz transient absorption spectroscopy

Perovskite photoconductivity is observed to be compatible with Drude response as described by Eq. 3.29. [100]

$$\sigma_d = \frac{\sigma_{dc}}{1 - i\omega\tau} \quad (3.29)$$

$\sigma_{dc} = \frac{ne^2\tau}{m}$  is the ohmic response of the conductivity. If the scattering rate of charge carriers is comparable to THz frequency, then both the real and imaginary parts of the photoconductivity are observed to be finite, and this can be used for the determination of mobility of free charge carrier by using the Drude response  $\mu = \frac{q\tau}{m^*}$ ;  $m^*$  is the effective mass of the electrons. [100] In terahertz absorption spectroscopy, pump (laser pulse beam as an excitation source) is used to generate free charge carrier and light



**Fig. 10** (a) Measurement of normalized photoconductivity transient versus pump-probe delay time of dual source vapor-deposited  $\text{MAPbI}_{3-x}\text{Cl}_x$ -based perovskite measured using pump-probe terahertz absorption spectroscopy at various excitation fluences showing domi-

nation of various regime of recombination processes by the decay rate of transient signal. [99] (b) Determination of total charge carrier mobility  $\mu = \mu_e + \mu_h$  using the real part of mobility determined from the transient absorption spectroscopy [74]



is used as a probe signal. Due to pump-induced charges, the change in electric field  $E$  is related to change in the photoconductivity of the sample given by Eq. 3.30. [100]

$$\frac{\Delta E}{E} \propto \frac{\Delta \sigma}{\sigma} \quad (3.30)$$

$\frac{\Delta \sigma}{\sigma}$  is known as the normalized photo conductivity, and  $\Delta \sigma$  is the transient response of photoconductivity of the semiconducting sample. Transient absorption spectroscopy generates signal as normalized photoconductivity with respect to delay time between pump and probe signals. Delay time between pump and probe signal is chosen such that it matches with the photoexcited relaxation process time. Transient photoconductivity signal at low fluence levels shows decay due to the monomolecular recombination channel as the fluence increases the other recombination channels also begins to respond, and this situation is shown in Fig. 10a.

**Case studies** In some of the early studies, Wang et al. [101] investigated the time resolved transient spectroscopy of MAPbI<sub>3</sub> in under-stoichiometric and over-stoichiometric condition of PbI<sub>2</sub>. Perovskite film with deficient PbI<sub>2</sub> concentration showed a faster relaxation time than the perovskite with excess PbI<sub>2</sub> concentration. Authors have attributed this slow dynamic to the surface passivation impact of excess PbI<sub>2</sub>. Figure 10a is the photoconductivity spectrum of mixed halide MAPbI<sub>3-x</sub>Cl<sub>x</sub>-based perovskite, and this spectrum can be used to extract the real and imaginary parts of the charge carrier mobility using the Drude model of electrical conduction. The real part of mobility which is the sum of electron mobility ( $\mu_e$ ) and hole mobility ( $\mu_h$ ) stays constant as shown in Fig. 10b. By assuming the equal mobilities for electrons and holes, the observed mobility values for electrons and holes were 20 cm<sup>2</sup>/V-s (Table 4).

## 4 Factors affecting recombination coefficients and their magnitude in perovskite

### 4.1 Photon recycling (PR)

Photon recycling (PR) is the repeated reabsorption of the spontaneously emitted photon due to radiative recombination. PR effect is observed to cause a reduction in the rate constant  $K_2$  because of large relative refractive index of perovskite-based semiconductors ( $n_r = 2-2.6$ ), [102] and radiatively emitted photons are observed to have low escape probability out of the device. [18]

Shockley and Queisser did not consider the impact of PR on the calculation of ultimate PCE limit for single

junction solar cells. PR is observed to enhance the overall photoluminescence yield and hence imparted to improve the  $V_{OC}$  of the solar cells significantly. [103] Total radiative current detected externally is given by Eq. 4.1. [18]

$$J_0^{rad,ext} = q \int_0^\infty \alpha(E) \phi_{bb}(E) dE \quad (4.1)$$

The relationship between radiative current generated internally and detected externally is given by Eq. 4.2. [18]

$$J_0^{rad,ext} = p_r J_0^{rad,int} \quad (4.2)$$

$p_r$  is known as the probability of recapturing the photon inside the semiconductor. The total internal radiative current generated due to the impact of PR is given by Eq. 4.3. [18]

$$J_0^{rad,int} = q \int_0^\infty 4\alpha(E) n_r^2 d\phi_{bb}(E) dE \quad (4.3)$$

The impact of PR on enhancement on the open circuit voltage of the solar is given by Eq. 4.4. [18]

$$\Delta V_{OC}^{PR} = \frac{KT}{q} \ln \left( \frac{J_0^{rad,int}}{J_0^{rad,ext}} \right) = \left| \frac{KT}{q} \ln(p_r) \right| \quad (4.4)$$

Through repeated absorption, bimolecular recombination constant also decreases by a factor as shown below in Eq. 4.5. [104]

$$K_2 = \frac{K_2^*}{1 - p_r} \quad (4.5)$$

where  $K_2$  is the modified radiative recombination constant (detected externally) due to the impact of PR inside the semiconductor material.

### 4.2 Rashba effect

Another effect that influences the rate of radiative recombination process in perovskite semiconductors is the Rashba effect. Magnetic field produced due to the spin orbit coupling in perovskite material splits the conduction and valance band edge in the  $k$  space. [105] The spin degenerated band edges will assign an overall indirect like bandgap characteristic to perovskite semiconductors. [106] Due to this indirect nature of the perovskite bandgap, the radiative recombination rate constant  $K_2$  is also observed to slow down. Radiative recombination is observed to be reducing due to the presence of spin-orbit forbidden transition between the photogenerated charge carriers. [105]

### 4.3 Polaron formation

Inside a highly polarizable lattice such as metal halide perovskites, atoms fluctuate more about their mean position; due to these atomic displacements, there exists a coupling between phonon produced due to the atomic displacement and charge carrier induced by the light absorption. Such Coulombic coupling interaction between polarons and free charge carrier forces electrons to be trapped inside a potential well created due to the atomic displacement of ions about their mean position. Polarizability of the medium is defined by reciprocal of the relative dielectric constant  $\epsilon(\infty)$  measured at the high-frequency regime of dielectric relaxation. Perovskite is observed as a highly polarizable semiconductor because of the small value of relative dielectric constant  $\epsilon(\infty)=5$ . [15] Based on the interaction between phonon and electrons, polarons are divided into two categories, long range polarons and small range polarons. [15] Large polarons exist over multiple lattice sites, while small polarons exist in a very short range only. [107] Small polaron formation in perovskite is also identified to be a probable reason for reversible photodegradation. [108] Further compositional engineering such as mixed cation perovskites are also observed to enhance the stability of the metal halide perovskite by the formation of small polarons. [109, 110] The binding energy of the large polarons is given by Eq. 4.6 [15] where  $R_p$  is known as the polaron radius.

$$E_p = -\frac{e^2}{4} \left( \frac{1}{\epsilon_\infty} - \frac{1}{\epsilon_0} \right) \frac{1}{R_p} \quad (4.6)$$

The coupling strength for large polaron distributed over multiple lattice sites is given by Eq. 4.7. [111]

$$\alpha_F = \frac{e^2}{h} \left( \frac{1}{\epsilon_\infty} - \frac{1}{\epsilon_0} \right) \sqrt{\frac{m}{2\hbar\omega}} \quad (4.7)$$

$\epsilon(\infty)$  and  $\epsilon(0)$  are the high and low-frequency dielectric constants of the semiconductor, and  $\omega$ ,  $m$  are the phonon frequency and effective mass of the electron respectively. Polarons are charged quasi particles; hence, a short-range repulsion between oppositely charged polarons always prevails. Polarons screen carrier-carrier scattering and carrier-defect scattering and hence assist in reducing the rate of the bimolecular recombination [112]. This short Coulombic repulsion is found to be decreasing the radiative recombination rate of the perovskite materials by repelling the photogenerated free charge carriers away from each other. Electrons and phonon in metal halide perovskite interact through two different interactions, i.e. acoustic deformation and Fröhlich interaction. [107] The acoustic deformation arises from the distortion in crystal structure due to the thermal vibrations of atoms, and it induces the interaction between acoustic phonon and electrons of the

semiconducting material. The Fröhlich interaction arises due to local electric field induced by the polarizability of the ionic lattice. As measured from time resolved terahertz spectroscopy, the charge carrier scattering time varies as  $\tau \propto T^{-1.5}$  where  $T$  the temperature of the device. [97] This kind of temperature dependence of scattering time is only observed when the charge carrier transport is limited by the scattering due to acoustic phonon only. Miyata et al. [112] studied large polaron formation in MAPbI<sub>3</sub> and CsPbBr<sub>3</sub>-based 3D perovskite and concluded that large polaron formation in perovskite is independent of the type of cation used. Large polaron formation was observed due to the deformation of PbX<sub>3</sub><sup>-</sup> framework, though polaron formation time was observed to be less in MAPbI<sub>3</sub> (0.3 ps) compared to CsPbBr<sub>3</sub> (0.7 ps) -based perovskite.

## 5 Defect passivation in perovskite

The photovoltaic performance of perovskite solar cell (PSC) is highly influenced by the presence of the defects in the perovskite absorber layer. To achieve the high PCE in PSCs, the defect passivation techniques are highly important. Most of the intrinsic point defects in perovskites are observed near to the band edges; however, deep level defects such as the migration of ions, interfacial defects and grain boundaries can gravely impact the stability and optoelectronic properties of perovskites. These defects can be prevented by using the different passivation strategies such as the introduction of cation or anion, [121, 122] additive approach, [123] suppression of ion migration, [124] grain boundary engineering, [125] interfacial engineering, [126] antisolvent method [127] and deposition method, [128] which are briefly discussed in the next section. We have also listed various defect engineering strategies and their outcomes in Table 5 studied on various APbX<sub>3</sub>-based perovskite materials.

### 5.1 Defect passivation using stoichiometric/non-stoichiometric material engineering

The Pb-based vacancies that can form deep level defects originate in the lead halide perovskite due to the excitonic stress [129], incomplete reaction [130], contamination and aging stress. [131] These defects or vacancies act as strong non-radiative recombination centers and hamper the long-term stability of the perovskites. The lead vacancies in MAPbI<sub>3</sub> can be prevented by the incorporation of excessive concentration of MAI in the precursor and keeping a deliberate Pb-I<sub>2</sub> deficient condition during the formation of precursor. Zhang et al. [132] have reported the passivation of lead vacancies in inorganic perovskite by introducing

**Table 5** Various defect engineering strategies employed in APbX<sub>3</sub>-based perovskite materials

Passivation technique	Passivation agent	Target defect	Mechanism	Perovskite material	PCE (%)	Reference
Material engineering	In situ PbI <sub>2</sub>	Halide vacancy	Strain relaxation	(FAPbI <sub>3</sub> ) <sub>1-x</sub> (MAPbBr <sub>3</sub> ) <sub>x</sub>	19.55	[140]
	I <sub>2</sub> /antisolvent washing	Halide vacancy	Filling	MAPbI <sub>3</sub>	21.33	[220]
Metal cation doping	Na <sup>+</sup>	MA vacancy	Substitutional filling	MAPbI <sub>3</sub>	15.14	[221]
	KI	MA and halide vacancy	Filling and immobilizing	(CsFAMA) <sub>0.9</sub> K <sub>0.1</sub> Pb(I <sub>0.85</sub> Br <sub>0.15</sub> ) <sub>3</sub>	21.50	[222]
Zwitterion	QAHs	Ion vacancy	Hydrogen bonding and electrostatic interaction	FA <sub>0.85</sub> MA <sub>0.15</sub> Pb(I <sub>0.85</sub> Br <sub>0.15</sub> ) <sub>3</sub>	21.00	[223]
Lewis acid & Lewis base	IPFB	Under coordinated I <sup>-</sup>	Halogen bonding	MAPbI <sub>3</sub> Cl <sub>3-x</sub>	15.70	[152]
	Pyridine	Under coordinated Pb <sup>2+</sup>	Coordinate bonding	MAPbI <sub>3</sub>	18.50	[224]
	DTA	Under coordinated Pb <sup>2+</sup>	Coordinate bonding	MAPbI <sub>3-x</sub> Cl <sub>x</sub>	21.45	[225]
Additives	Zinc porphyrin	Under coordinated Pb <sup>2+</sup>	Coordinate bonding	Cs, FA, MA perovskite	20.50	[226]
Interfacial layer passivation	F4TCNQ	Metallic lead	Coordinate bonding	MAPbI <sub>3</sub>	16.07	[227]
	Fullerene derivative	PbI <sub>3</sub> <sup>-</sup> antisite (at grain boundary)	Coordinate bonding	MAPbI <sub>3</sub>	17.63	[228]
	PTTA	Ion migration	Grain boundary passivation	MAPbI <sub>3-x</sub> Cl <sub>x</sub>	19.04	[126]
	PMMA	I <sup>-</sup> vacancy	Coordinate bonding	Cs <sub>0.07</sub> Rb <sub>0.03</sub> FA <sub>0.765</sub> MA <sub>0.135</sub> PbI <sub>2.5</sub> Br <sub>0.45</sub>	20.40	[229]
Film passivation	Heat	Halide vacancy, ion migration	Strain relaxation, grain boundary passivation	MAPbI <sub>3</sub>	15.60	[230]
	VASP	Ion migration	Grain boundary passivation	FA <sub>0.81</sub> MA <sub>0.15</sub> PbI <sub>2.55</sub> Br <sub>0.45</sub>	20.47	[231]

the anionic doping. The defect states were observed to reduce with the introduction of PbI<sub>2</sub>-rich and PbI<sub>2</sub>-poor precursors. The excess amount of PbI<sub>2</sub> was observed helping in the formation of coordination bond between the two grain boundaries, which leads to the non-stoichiometric compositional growth condition. The PbI<sub>2</sub>-rich precursor was observed to reduce the defect density by passivating the local grains. [133, 134] Furthermore, PbI<sub>2</sub>-poor precursor has also been observed to reduce the deep level interstitial iodine vacancies in MAPbI<sub>3</sub> crystal.

## 5.2 Defect passivation of metal cations and anions in perovskite semiconductors

The A-site, B-site and X-site defects in ABX<sub>3</sub> perovskite structure can be passivated with the introduction of various selective cations and anions. Because of the cations/anions interaction with the defect site of the ABX<sub>3</sub> by donating/accepting the electrons, defect passivation bonds are observed to form among the selective cations or anions with the defect sites. The cations are observed to passivate the A-site, B-site defects, and anions are observed to

passivate the X-site defects respectively in the ABX<sub>3</sub> perovskite structure. A-site, B-site and X-site defect passivation can be established by incorporating the different metal cations and anionic passivators in the perovskite material. There are several metal cations reported for passivating the negatively charged defects, which are created by the migration of A-site cation, B-site cation and antisite defects in ABX<sub>3</sub> perovskites. These negatively charged defects can be passivated with the introduction of monovalent metal cations such as Na<sup>+</sup>, K<sup>+</sup>, Rb<sup>+</sup>, divalent metal cations Mn<sup>2+</sup>, Ni<sup>2+</sup>, Cd<sup>2+</sup>, Ca<sup>2+</sup>, Sn<sup>2+</sup>, and trivalent metal cations Al<sup>3+</sup>, Eu<sup>3+</sup>, Bi<sup>3+</sup>. [135] Since Na<sup>+</sup> ion has the similar atomic radius as the MA<sup>+</sup>, so it can be used for the A-site vacancy passivation in the perovskite. Na<sup>+</sup> ion is observed to passivate the grain boundaries by forming the ionic bond with negatively charged defects present at the boundaries and also observed to enhance the grain size of perovskite crystals, which facilitate the formation of pinhole-free perovskite films. [131, 136, 137]. Son et al. [121] reported the migration of A<sup>+</sup> site cation is the primary reason for the observed JV hysteresis in perovskite-based device, and the hysteresis effect has been suppressed by incorporating the optimum amount of

$K^+$  ions. The atomic size of  $K^+$  is well suited to occupy the octahedral interstitial sites and prevented the  $I^-$  migration by forming the ionic bond with  $I^-$ . B-site defects are observed to be passivated by doping the perovskite with the divalent cation and alkaline earth metal cations. [138–140] The divalent metal cations are observed to form coordination bond with the halides present in the perovskite. Doping with  $Cd^{2+}$  ion is observed to increase the vacancy formation energy at the B-site by suppressing the ionic migration and creating the lattice strain. To overcome such a high activation energy barrier by the B-site cations is very difficult, which results in the defect passivation of the B-site cation in perovskite. [139] The positively charged defects in halide perovskites are observed due to the lack of coordination between Pb ions, iodine vacancy and antisite defects. The commonly used anionic passivators for defect passivation are  $F^-$ ,  $Cl^-$ ,  $Br^-$ ,  $I^-$  and the halogen functional groups. [141] Li et al. [122] used NaF as an anionic passivator for the halide perovskite and observed  $F^-$  anion creates hydrogen like bonding with the A-site cation, which provided the important surface stability to the perovskites structure. Tan et al. [142] have reported the X-site defect passivation with  $Cl^-$  as an effective passivating agent at the interface by forming Pb-I antisite and Pb-Cl antisite. The defect formation energy of Pb-Cl antisite was observed higher than the Pb-I antisite, which indicates the antisite defects were suppressed with the presence of interfacial Cl atoms. Thus, selective anionic passivators are capable of passivating uncoordinated halides via the hydrogen bonding.

### 5.3 Grain boundary defect passivation engineering

Defects are usually accumulated at the grain boundaries, and these grain boundary defect are observed to act as strong non-radiative recombination centers. To overcome this problem several additives engineering have been reported by the various researchers such as the introduction of zwitterions, Lewis acids (e.g. fullerene and their derivatives) [143], Lewis bases (O donor, S donor, N donor) for the passivation of grain boundary defect [144], and these grain boundary passivation strategies are discussed below in the next section.

#### 5.3.1 Defect passivation by using the zwitterions

The individual anionic and cationic passivators as discussed in the previous section are only capable of passivating a single kind of point defect at a time, but zwitterions are observed to passivate both the negatively and positively charged point defect simultaneously. The most commonly used zwitterion passivators are mainly metal-based small molecule and organic molecules. Incorporation of  $ChCl$  zwitterion to the  $MAPbI_3$  perovskite is observed to reduce

the  $MA^+$  cation-based defects on the perovskite surface by occupying the octahedral positions, and  $Cl^-$  ion is observed to passivate the  $PbI_3^-$  antisite defects. [145]

#### 5.3.2 Defect passivation by using the Lewis acid

The uncoordinated  $I^-$  and antisite  $PbI_3^-$  act as a deep recombination center when present near the surface and grain boundaries of  $MAPbI_3$  thin film, and these states can be passivated by using the Lewis acid. Fullerene and their derivatives [143, 146, 147] have proven as the most effective defect passivator because they are observed to have excellent electron-accepting properties and also observed to create the strain inside the perovskite thin film. Shao et al. [143] reported that Lewis acids can make stronger hydrogen like bonding with uncoordinated  $I^-$  and antisite  $PbI_3^-$  defects. The formation of hydrogen bond increases the charge transfer at the interface, which helps in passivating the defect present at the perovskite surface.

#### 5.3.3 Defect passivation by using the Lewis base

Lewis bases have characteristics of donating a pair of non-bonding electrons; these nonbonding electrons are capable of making bond with uncoordinated  $Pb^{2+}$  or Pb clusters present in perovskite and passivate them by forming the adducts. Noel et al. [144] reported Lewis base defect passivation by using the nitrogen and sulphur functionalities molecules having the capability of donating the pair of nonbonding electrons. deQuiletters et al. [148] have investigated trioctylphosphine oxide, octadecanethiol and triphenylphosphine Lewis base for defect passivation in perovskites. Authors have demonstrated the passivation capabilities of Lewis bases and found enhancement in PL lifetime of charge carriers from 0.9 to 8.85  $\mu s$ . Some other reports also highlighted the importance of reduced graphene oxide, thiophene, pyridine and amine containing compound reported as an effective Lewis base defect passivator. [149–152]

#### 5.3.4 Defect passivation by using the additives

The additives also play a vital role in defect passivation of the perovskite thin films. Tsai et al. [153] incorporated 1,8-diiodooctane (DIO) into the perovskite precursor and observed the uncoordinated Pb ions coordinated with DIO, which passivated the negatively charged defect and enhanced the overall PCE of perovskites. Zhao et al. [154] introduced the excess amount of  $MACl$  into perovskite precursor solution; authors have found due to its conformal characteristic, it helps in reducing the undesirable defect branches in perovskite crystals. Hu et al. [155] reported the significant improvement in the stability of perovskite with the addition of rare earth metal, and the device was observed to retain 90% PCE for 1700 h at elevated temperature.



## 5.4 Interfacial engineering

Since passivating agent is observed to dissolve inside the perovskite precursor solution, there always exists a deviation in the bulk properties compared to the surface properties of perovskite, which leads to the introduction of interface-induced recombination. [156, 157] The interface-induced recombination can be prevented by making use of interfacial engineering. Zhang et al. [158] introduced ultrathin polarized ferroelectric polymer at the perovskite interface and obtained an optimum favorable energy band alignment for high efficiency perovskite-based solar cell. Zhou et al. [159] through controlled formation of the absorber layer and maintaining good carrier extraction at the electrodes by reducing the non-radiative recombination at the interface managed to improve the PCE significantly from 16.6 to 19.3%. Recently, researchers have also reported the mechanism of back transfer recombination process at the interface by using the poly (3-hexylthiophene) as a hole transport layer, which decreases the back transfer recombination process at the HTL/perovskite interface. [160] PC<sub>61</sub>BM and PMMA explored as a buffer layer between the ETL and perovskite layer are observed to suppress the interfacial recombination centers. [161, 162] The conjugated electrolyte introduced between the PTAA and perovskite is also observed to reduce the detrimental interfacial defect. [163] To enhance the PCE beyond 20% for the *p-i-n* perovskite-based solar cell, Albrecht et al. [164] reported replacement of polymer hole selective layer with the self-assembled monolayer of carbazole-based phosphonic acid. The introduction of LiF between [163, 165] the ETL/perovskite layer was observed to reduce the C<sub>60</sub>/perovskite interface losses and led to enhancement in the  $V_{OC}$  of the solar cell. Jeong et al. [166] reported an effective and simple interface engineering strategy by introducing the cost-effective, stable and dopant-free HTM polymer gallium(III) acetylacetonate into poly(3-hexylthiophene), and devices showed remarkable improvement in the PCE (~24.6%). Recently, several other effective techniques were also reported to passivate the interfacial defects with the application of various interlayers such as polymer, oxides and fullerene derivatives. [161, 167–170]

## 5.5 Antisolvent vapor-assisted crystallization

Antisolvents cannot dissolve the solute particles but are miscible with the solvent of the solution. In this process, antisolvent interaction with the precursor solution of perovskite makes the overall solution to a supersaturated level, and the supersaturated solution further undergoes coprecipitation process; thus, the high-quality perovskite films are formed. Single-crystal perovskite grown using the antisolvent vapor-assisted crystallization is observed having the superior optoelectronic performance such as

mobility, charge carrier diffusion length, charge carrier lifetime compared to microcrystalline perovskite thin films. [171–173] Since growing single crystal on a substrate requires high nucleation formation energy, antisolvent vapor-assisted crystallization is observed to generate an ultrasonic pulse, which results in overcoming the barrier to form a nucleus on the surface of the substrate and provided a defect-free high quality crystalline film of perovskite. [174] The boiling point of solvents (DMF and DMSO) used in the perovskite film synthesis is high, and hence the solvent evaporation rate during spin coating process is low, which hampers the crystallization process and caused the formation of defects in the film. With the addition of non-polar solvents in antisolvent dripping, the solubility of perovskite in solution is reduced, and hence it promotes the effective nucleation and crystallization. [171, 175] Hossein et al. [176] investigated the role of antisolvent optimum temperature for dripping during spin coating process to achieve the best quality films. Wen et al. [177] reported controlled supersaturation and nucleation rate with the mixed antisolvent by optimizing the different antisolvent ratio, which contributed towards growth of large crystalline grain boundaries. The thermodynamics of nucleation process for the various antisolvents have been reported by Liu et al. [178] which provided the crystallization kinetics of perovskite thin film by incorporating the various antisolvents. Tidhar et al. [127] reported the passivation of defect using the antisolvent vapor-assisted crystallization method by alcohol-based antisolvents for MAPbBr<sub>3</sub> perovskite. Shi et al. [179] replaced the alcohol-based antisolvent with the dichloromethane (DCM) and produced a defect-free MAPbI<sub>3</sub>-based single crystal material. Green antisolvents such as petroleum ether, ethyl acetate and iso propanol, ethers diethyl ether, anisole, diisopropyl ether (DIE) are also employed during the fabrication of perovskite-based solar cells. [180–183]

## 5.6 Optimization of thin film formation

Various processing techniques provide unique perovskite film properties based on the phase formation and the formation of the defect states. [128, 184–186] The kinetics and thermodynamics parameters of these techniques are governed by tuning the annealing temperature, ramping rate, time and introduction of various solvents. [187] Vacuum deposition technique has poor control on the temperature of reactant species and substrate, which leads to nonideal stoichiometry in the thin films of the perovskite. Several concepts are reported regarding improving the morphology of the thin film formation and to minimize the defect density in the perovskite films. These are the incorporation of mesoporous particles and different phase formation with the optimized annealing process. [188–190] Xiao et al. [191]



studied the inter-diffusion of perovskite precursor to tune the composition of the perovskite films.

## 5.7 Other recent defect passivation strategies

Several recent defect passivation strategies have been reported by various research groups as the surface passivation of the perovskite layer, conversion of extended imperfection to wide bandgap and surface passivation of the carrier transport layer. [192–194] Surface passivation techniques to reduce the detrimental surface defect and dangling bonds have widespread application even in the state-of-the-art commercialized silicon [195–197] as well as GaAs [198, 199]-based solar cells. Surface states and dangling bonds cause deep level defects in bandgap of the semiconductor materials. The contribution of the surface states to the non-radiative recombination process is mainly accessed by the surface recombination velocity. In principle, an ideal surface having zero recombination due to the absence of surface states has zero surface recombination velocity. While extremely bad surfaces having infinite recombination centers have infinite surface recombination velocity. Surface passivation techniques to mitigate defects at the surface have also started to gain attraction in perovskite-based solar cells. He et al. [200] used triphenyl(9-ethyl-9H-carbazol-3-yl)-phosphonium bromide (TCPBr) and iodide (TCPI), as a surface passivator in between the HTL and perovskite interface. Authors have confirmed the effectiveness of surface passivation by measuring the charge carrier dynamics at the HTL/perovskite interface by using the TRPL spectroscopic technique. The increase in PCE and reduction in the hysteresis behavior of the fabricated solar cell were assigned to the effect of surface passivation of the perovskite layer. Further, the hydrophobic nature of the passivating agents was also observed to reduce the moisture penetration and prompted the device stability. Cao et al. [201] modifies the poor chemical compatibility of ZnO ETL layer with the perovskite absorber by passivating the ZnO surface using the thin layer of MgO and protonated ethanolamine (EA). Because of the surface passivation effect, perovskite solar cell with high PCE and hysteresis free device was obtained. The device was observed to be air stable for 300 h when encapsulated by the graphene layer. Jokar et al. [202] studied the doping effect of bulky organic cations with ethylene diammonium diiodide ( $\text{EDAI}_2$ ) and butylammonium iodide (BAI) as additives to passivate the lead free perovskite  $\text{FASnI}_3$  surface. Addition of BAI additive altered the perovskite crystal orientation growth, while  $\text{EDI}_2$  facilitates the formation of pinhole free thin film and suppresses the oxidation of  $\text{Sn}^{2+}$  state to the  $\text{Sn}^{4+}$  state. Small molecular material such tetratetracontane ( $\text{TTC}, \text{CH}_3(\text{CH}_2)_{42}\text{CH}_3$ ) incorporated by Li et al. [203] at the fullerene/perovskite interface assisted in reduction of

the electron recombination and enhancement in the PCE of the planer perovskite device. Due to the hydrophobic nature of the small molecular material device, it retained 87% of its PCE in air under the constant exposurer. Jiang et al. [194] introduced the organic halide salt phenethylammonium iodide (PEAI) layer at the interface of FA-MA mixed perovskite and HTL. Through TRPL study, authors confirmed the surface passivation impact of the PEAi material by obtaining an efficient photo generated charge carrier extraction. The obtained  $V_{\text{OC}}$  of the device was matched with 94.4% of its Shockley–Queisser limit. Novel indacenodithieno(3,2-b) thiophene (IDTT-ThCz)-based small molecule (SM) as additive developed by Choi et al. [204] facilitates the surface passivation of the perovskite surface. The fabricated device using passivated perovskite surface was observed to retain 95% of its PCE up to 500-h storage at elevated temperature condition ( $85^\circ\text{C}$ ). The ionic defects at the surface and grain boundaries usually passivated through Lewis acid, Lewis base or through ionic bonding passivation mechanism. However, another way to passivate the surface and grain boundaries defects is by chemically converting the extended imperfections to the wide bandgap materials. [205, 206] The wide bandgap hinders the charge transfer between the perovskite grains and interface by creating the electronic barrier, and when the charge reaches to the wide bandgap wrapping layer, these charges are reflected back into the bulk and thus passivate the grain boundaries and interfacial defects. The choice of charge transport material also plays a crucial role to get high performance of PSCs since at the interface band bending, charge accumulation and dipole generation are widely present. [207] Thus, charge transport layer must be optimized to achieve a favorable energetic alignment and have a good charge transfer interface with the active perovskite layer. Various charge transport layer (CTL) passivation strategies have been also reported such as by using the various additives, PTTA [208], EDTA [209],  $\text{NH}_4\text{Cl}$  [210],  $\text{Cl}_2$  [211]. Abuhelaiqa et al. [211] explored doping of  $\text{SnO}_2$  charge transport layer with tin-bis-(acetylacetonate) dichloride and tin-bis-(acetylacetonate) dibromide and observed the defect passivation effect of  $\text{SnO}_2$  layer. Other doping methods to improve the performance of CTL is by the introduction of  $\text{Cu}^+/\text{Li}^+/\text{Mg}^{+2}$  metal cations inside the CTL to enhance the conductivity. [212] Okada et al. [213] deposited the mixed layer of polyvinyl carbazole and PCBM over  $\text{TiO}_2$  CTL and observed the significant improvement in the PCE. The deposition of dense  $\text{SnO}_2$  layer at the interface by ALD method is also observed to improve the performance of CTL in perovskite-based solar cells. [214] The practical application of PSCs is limited due to poor stability, and large efforts have been made to enhance the stability of PSCs. Those efforts are through the device encapsulation [215], interface engineering [194], phase stabilization

[216] and grain boundary passivation [217] to achieve the device longevity. The operational stability of PSCs is highly dependent upon migration of charge defects inside the ionic perovskite crystal. These charged defects can be passivated by the introduction of different molecular passivator, but during the high temperature and high humidity condition these secondary bonds formed between passivator molecule and perovskite gets easily broken which reduces the passivation effect. [218] To address this issue, Zhao et al. [219] reported strategically designed passivating agents to investigate the effect of the various functional group and their interaction energies with the perovskite ionic defects, which also provided the correlation between the performance and longevity of the passivation effect.

## 6 Conclusions

In this review, we have discussed the fundamental physics of defect formation, recombination mechanisms and various characterization techniques to estimate the defects and recombination pathways. Using thermodynamics and first principle calculations, we have summarized the formation energy of the various point defects based on their location in perovskite material energy bandgap. Ionic migration of  $\text{MA}^+$ ,  $\text{Pb}^{2+}$ ,  $\text{I}^-$  into the vacant sites and on the basis of defect formation energy,  $\text{MA}_\text{I}$  and  $V_{\text{Pb}}$  defects are observed to be the dominating point defect type in pristine perovskite. Perovskite semiconductor despite having presence of large numbers of point defects displays unique defect tolerance nature where physical properties such as charge carrier mobility and lifetime are observed to be unaltered by the bulk point defects. We have described the role of various defects in the different recombination process, whereas deep level defects impact the photovoltaic performance significantly by acting as strong non-radiative recombination centers in perovskite semiconductor. Bimolecular recombination mechanism in perovskite semiconductor is a complicated phenomenon affected by various other processes such as formation of polarons, Rashba effect and photon recycling. The value of bimolecular recombination rate in perovskite is observed to be very close to high quality crystalline inorganic semiconductor GaAs. [87] By using various spectroscopic characterization techniques such as capacitance, photoluminescence, electroluminescence, transient terahertz spectroscopy, it is possible to analyze the role of defects on the recombination losses in perovskite-based solar cells. Quenching of photoluminescence yield and photoconductivity is utilized to determine the effective bulk lifetime of charge carriers in the perovskite thin films. Using the capacitance spectroscopic measurements, various researchers highlighted the importance of surface and interfacial defects being the most

determinantal for the perovskite devices. Although researchers still need to explore the impact of point defects on the device parameters, also the individual contribution of point defects and interfacial defects still needs to be identified. Other complementary techniques such as space charge limited current (SCLC) method [50, 232–236], electron beam induces current (EBIC) method [237], scanning kelvin probe microscopy [44, 238], X-ray diffraction spectroscopy [239], positron annihilation spectroscopy [240] are also widely explored to determine the impact of defects and impurities in perovskite material. Lastly, we have discussed the various physical and chemical defect passivation techniques for the bulk, grain boundaries and interface defect passivation in perovskite-based thin films solar cells. Various point defect passivation strategies such as incorporation of metal cations/anions, zwitterions, additives, Lewis acid and Lewis base are discussed briefly. Other strategies for the perovskite/contact interface defect passivation, antisolvent vapor-assisted crystallization and thin film optimization are also summarized. Based on our study, currently the defect detection and defect passivation in perovskite semiconductor are highly challenging tasks and require a range of experimental techniques and experimental defect passivation strategies, but in terms of increasing the photovoltaic performance of perovskite solar cell these exercises are observed to be highly fruitful. Detailed study of bulk defect and surface defect contribution is also absolutely critical for the further enhancement of the power conversion efficiency in perovskite solar cell after the initial surge. The linkage between the kinetics of defect formation and stability of perovskite material is still a gray area. Majority of studies discussed in the review are based on archetypal perovskite which contains complicated interaction between organic and inorganic constitute at atomic scales, and there is no reason to believe that pure inorganic-based perovskite will also behave the same way as the hybrid perovskite. So, the defect study related to the other novel perovskite-based semiconductor still demands further attention since various perovskite-based semiconductor offers different functionality of physical parameters of its own. In a nutshell, this review provides a comprehensive overview of the defect formation, defect recombination and defect mitigations strategies in perovskite-based semiconductor as well as perovskite-based solar cells.

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## Declarations

**Conflict of interest** The authors declare no competing interests.

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